

# ANALYSIS OF THE ELECTRO-OPTICAL FRONT END FOR THE NEW 40 GHz BUNCH ARRIVAL TIME MONITOR\*

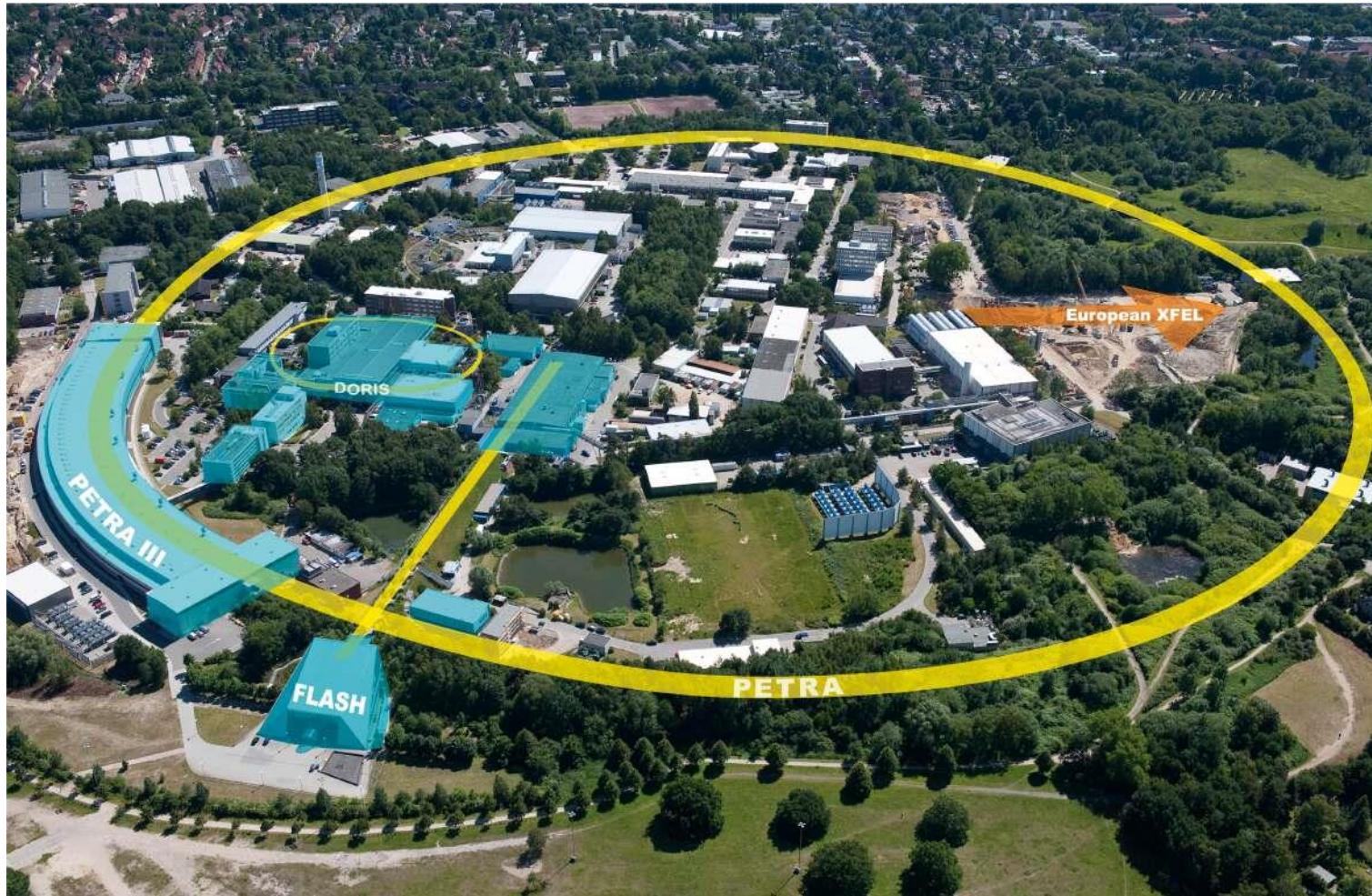
IBIC2012, Tsukuba, Japan, Oct 1-4, 2012

\*The work is supported by Federal Ministry of Education and Research of Germany (BMBF) within FSP 301 under the contract numbers 05K10GU2 and 05K10RDA.

# Outline

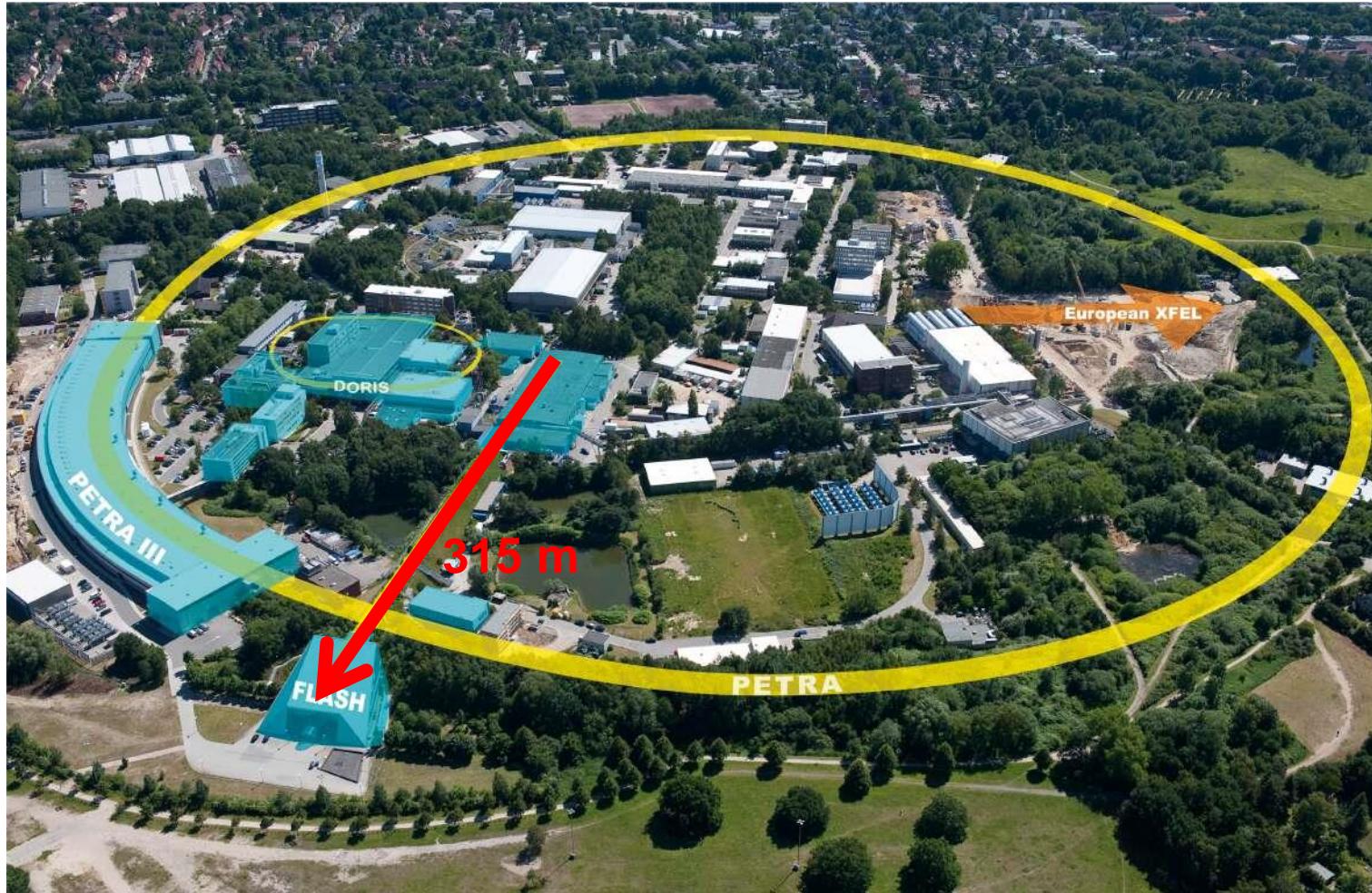
- Introduction
- Synchronization of FLASH
- BAM system
- Old and new Pickup
- RF calculation
- Monte Carlo Simulation
- Results
- Outlook

# Introduction



Picture: [www.desy.de](http://www.desy.de)

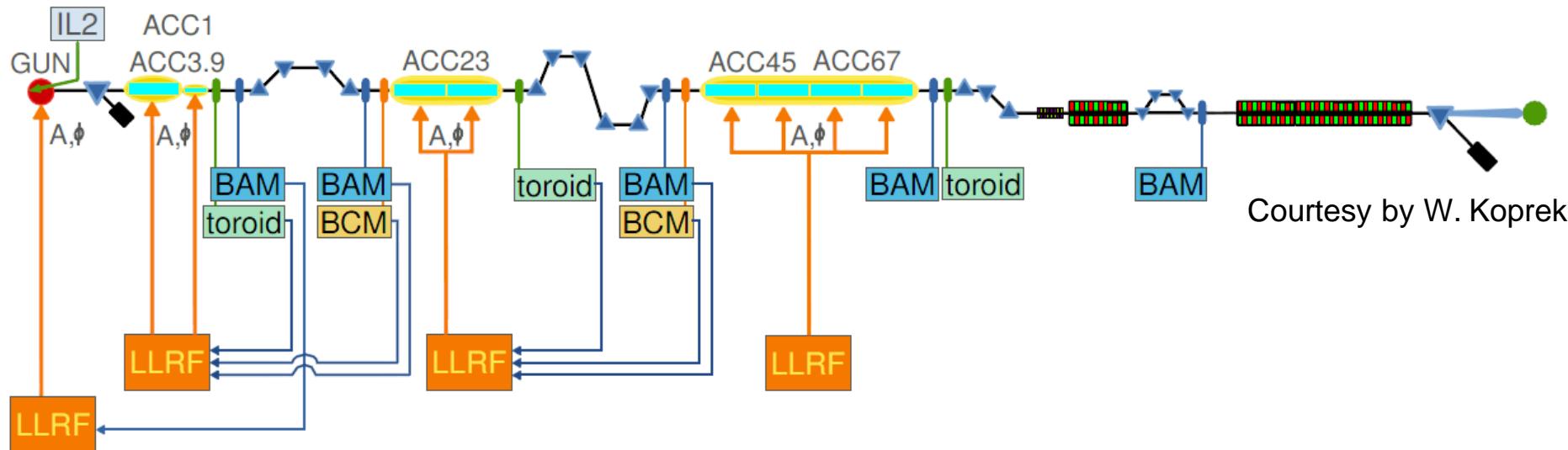
# Introduction



Picture: [www.desy.de](http://www.desy.de)

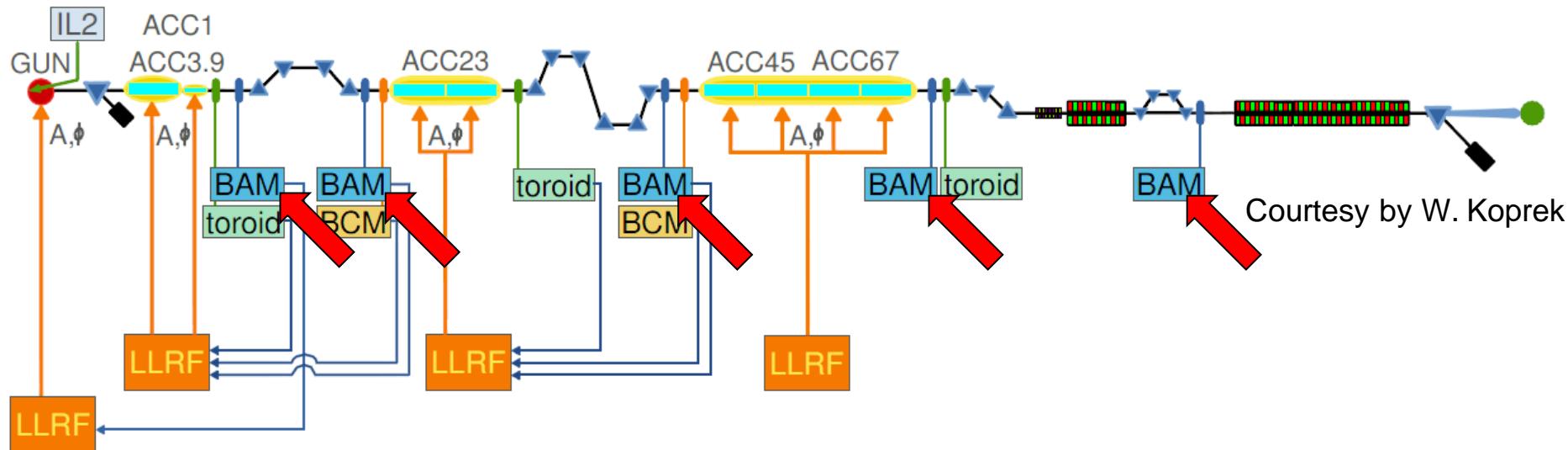
# Synchronization of FLASH

## The FLASH Accelerator



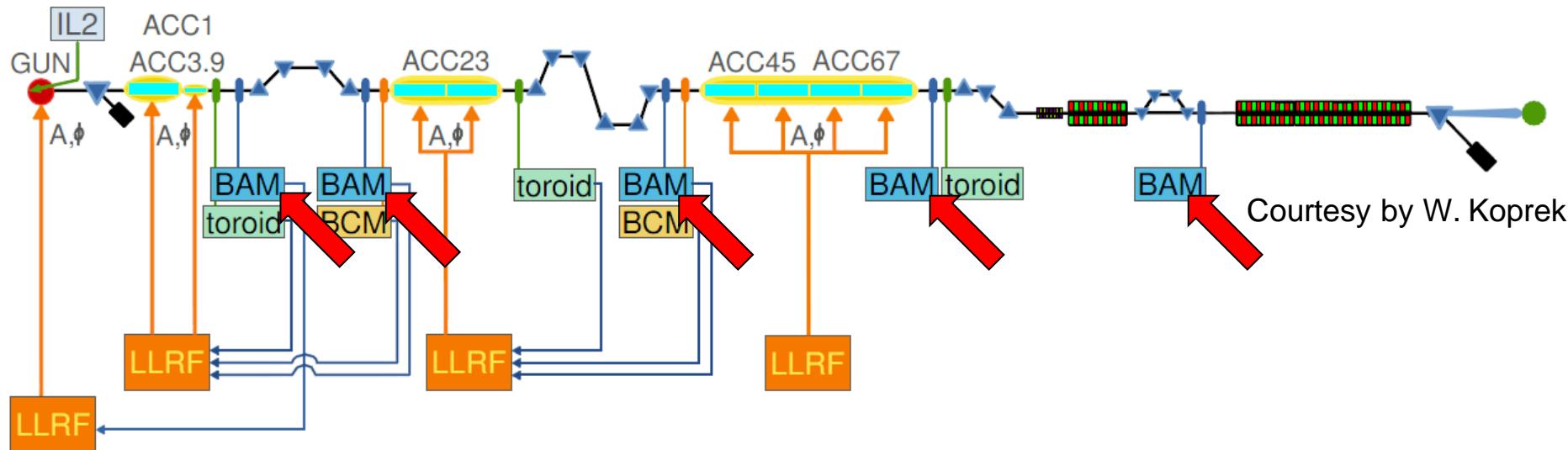
# Synchronization of FLASH

## The FLASH Accelerator



# Synchronization of FLASH

## The FLASH Accelerator



Accuracy of arrival time measurement:

< 10 fs

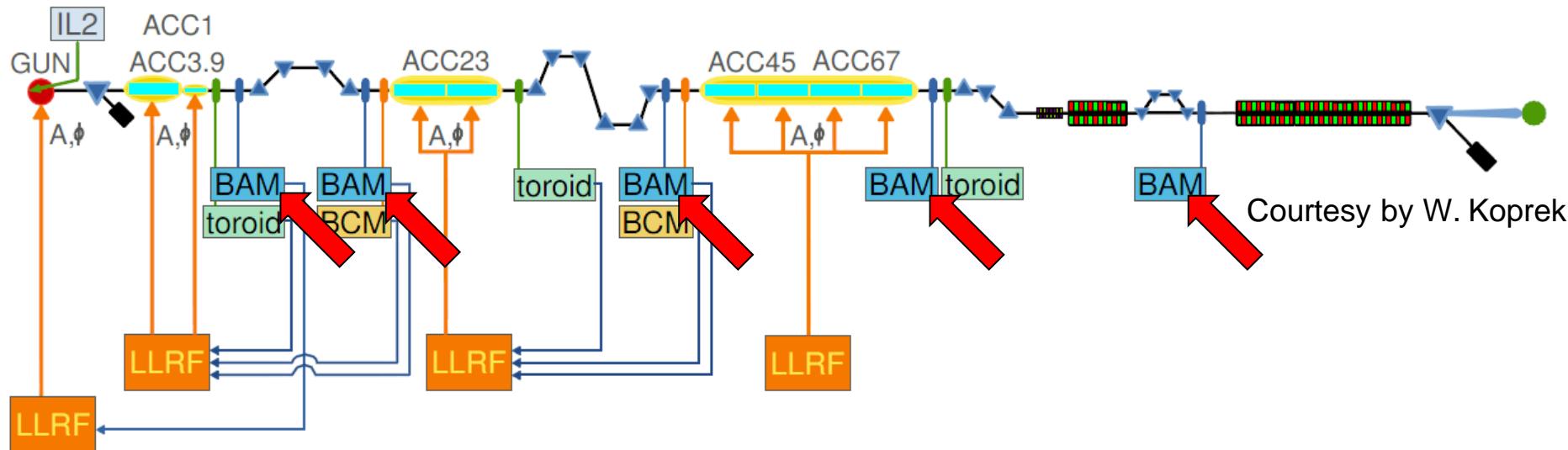
Reachable beam stability with feedback:

< 25 fs

Bunch charge > 500 pC

# Synchronization of FLASH

## The FLASH Accelerator



Accuracy of arrival time measurement:

< 10 fs

Reachable beam stability with feedback:

< 25 fs

Bunch charge > 500 pC

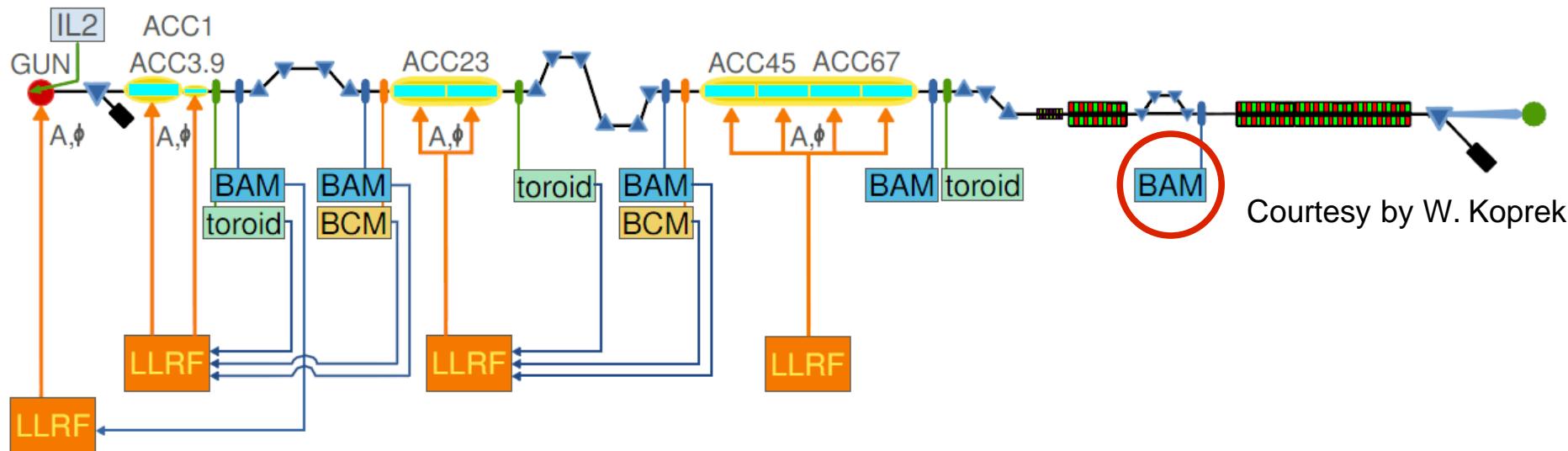


New requirement:

Accuracy of arrival time measurement = 10 fs with 20 pC bunch charge

# BAM system

## The FLASH Accelerator



Accuracy of arrival time measurement: < 10 fs  
Reachable Beam stability with feedback: < 25 fs

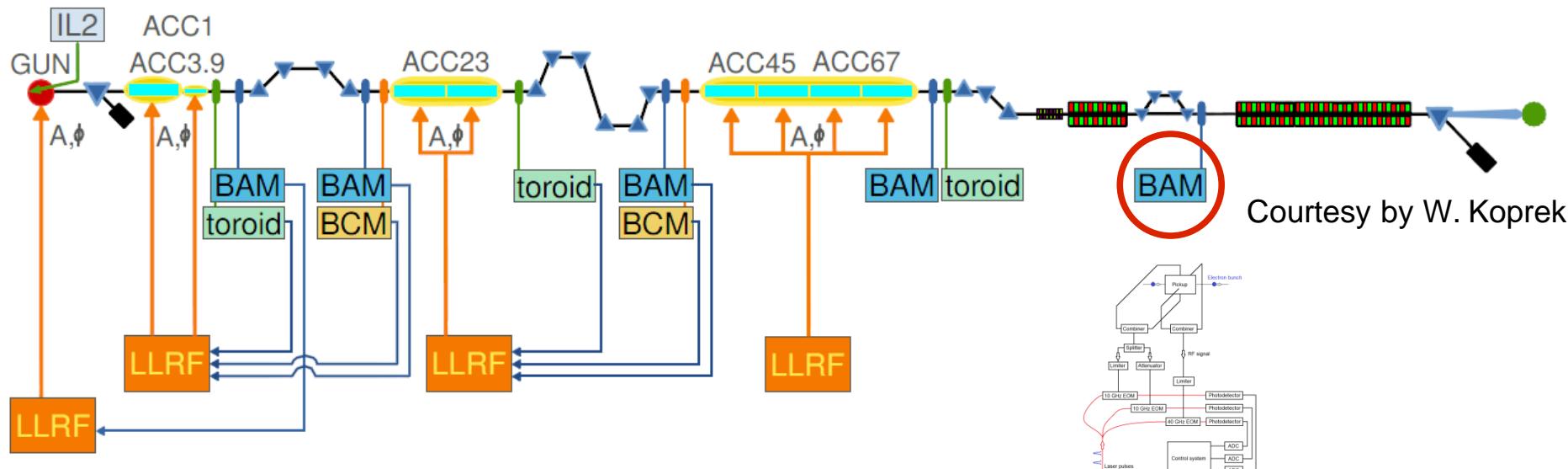
Bunch charge > 500 pC

→ New requirement:

Accuracy of arrival time measurement = 10 fs with 20 pC bunch charge

# BAM system

# The FLASH Accelerator



Accuracy of arrival time measurement:  
Reachable Beam stability with feedback:

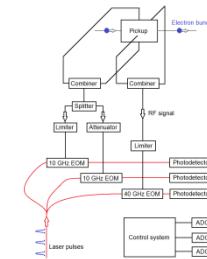
< 10 fs  
< 25 fs

# Bunch charge > 500 pC

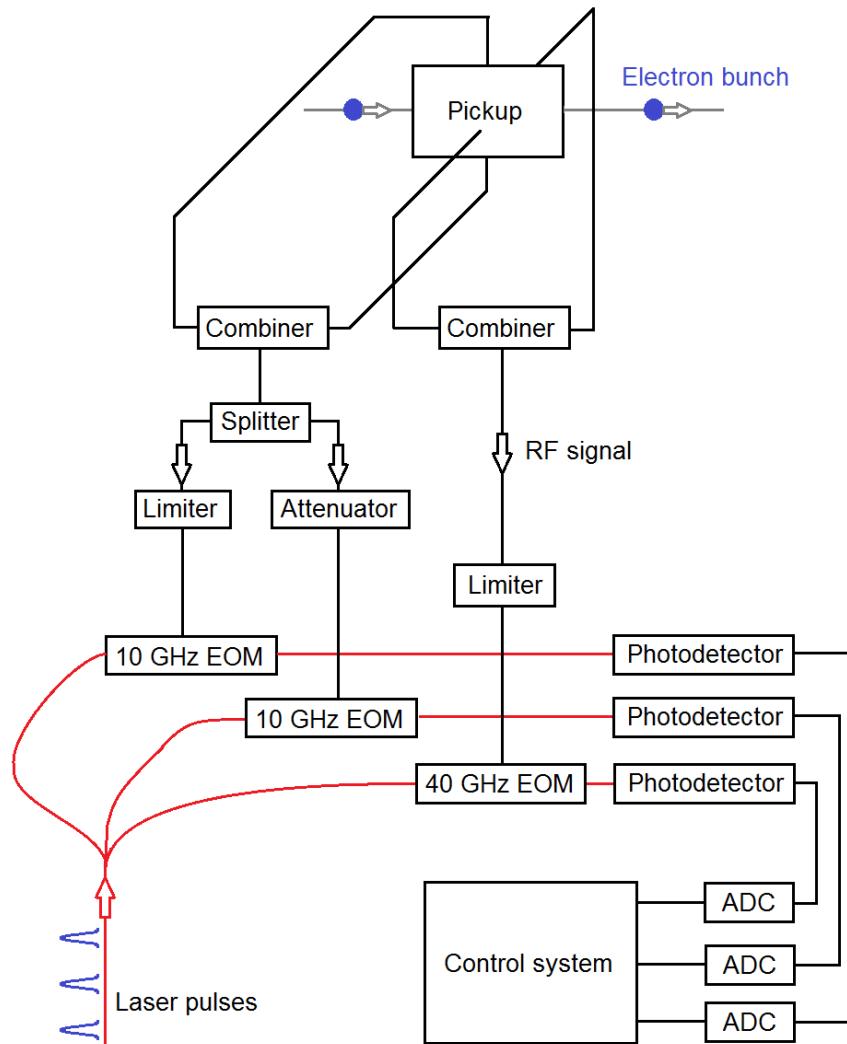
## New requirement:

Accuracy of arrival time measurement = 10 fs with 20 pC bunch charge

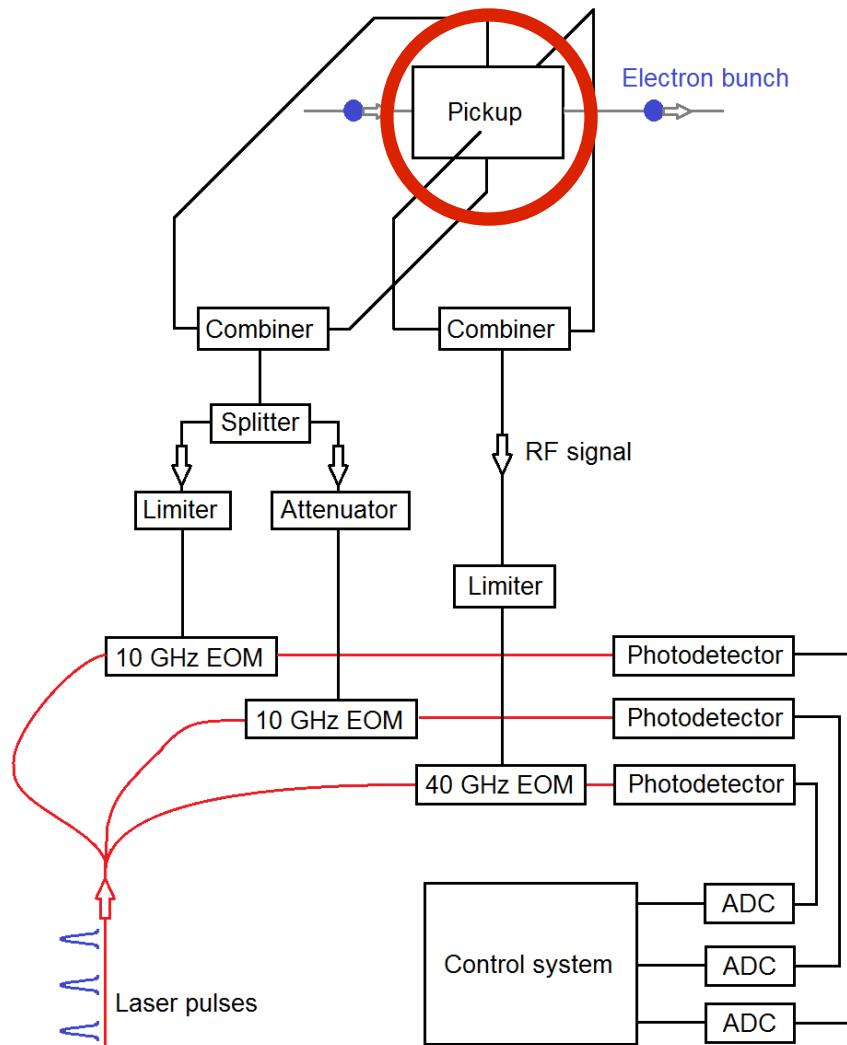
# BAM system



# BAM system

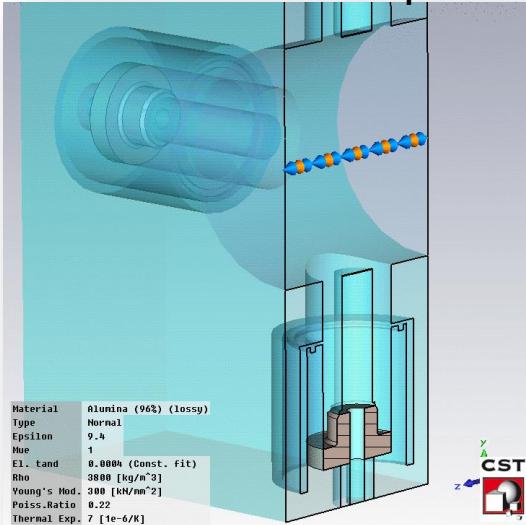


# BAM system

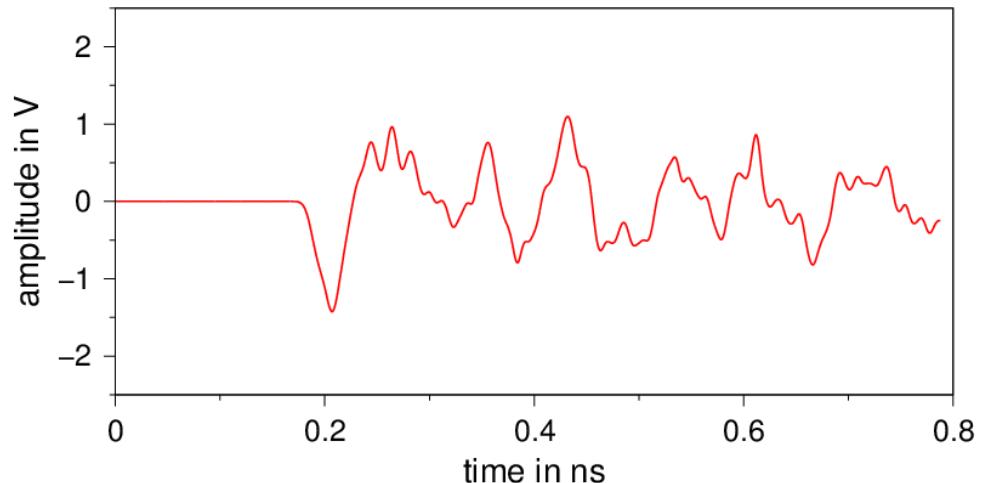


# Old and new Pickup

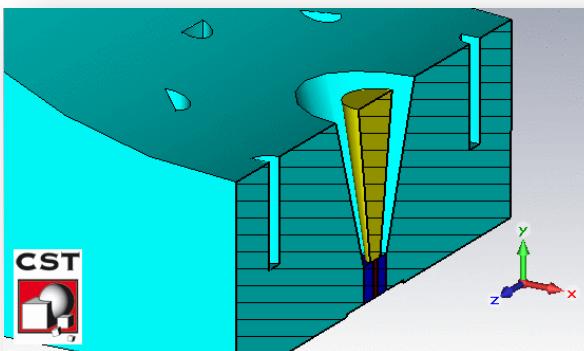
Old 10 GHz Pickup



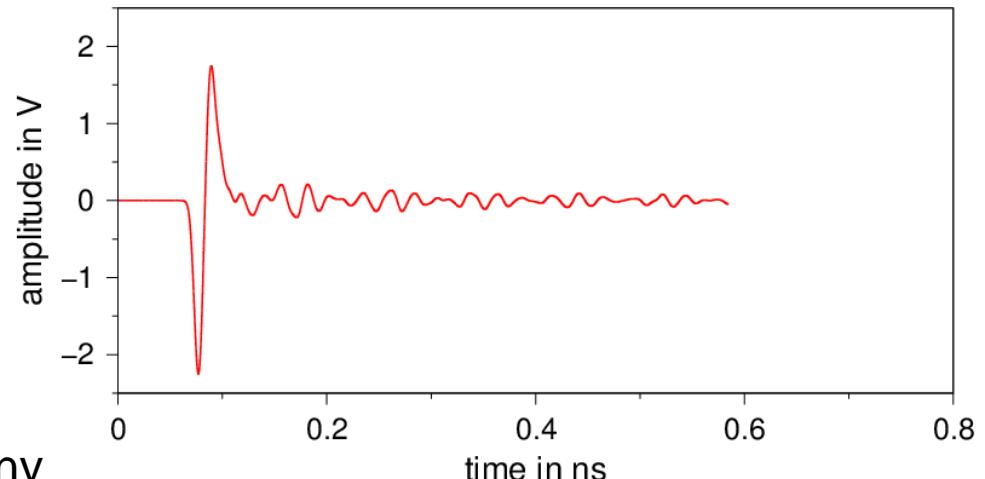
Simulation with 20 pC bunch charge



New 40 GHz Pickup

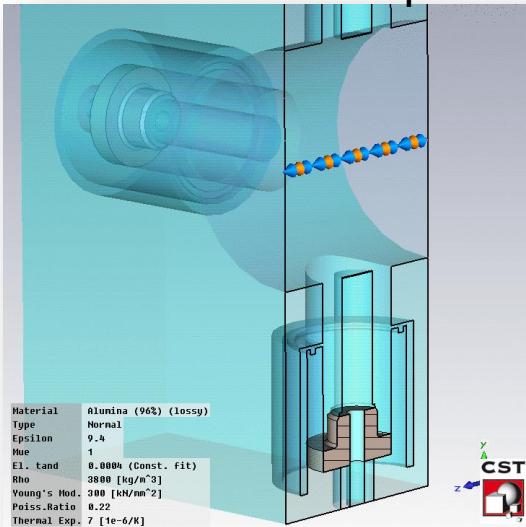


Design at TU Darmstadt, Germany

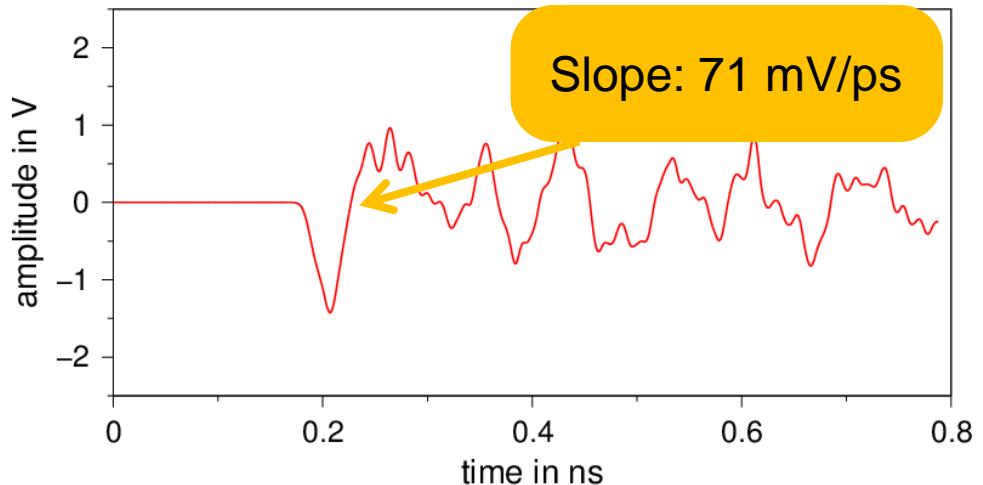


# Old and new Pickup

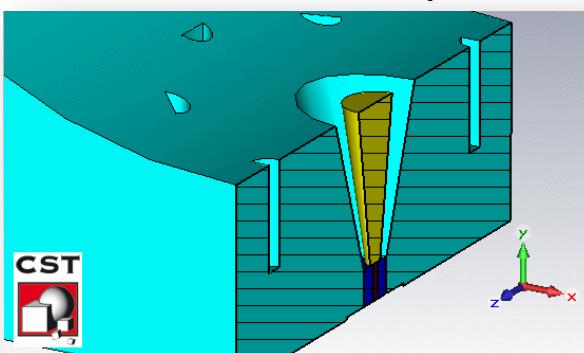
Old 10 GHz Pickup



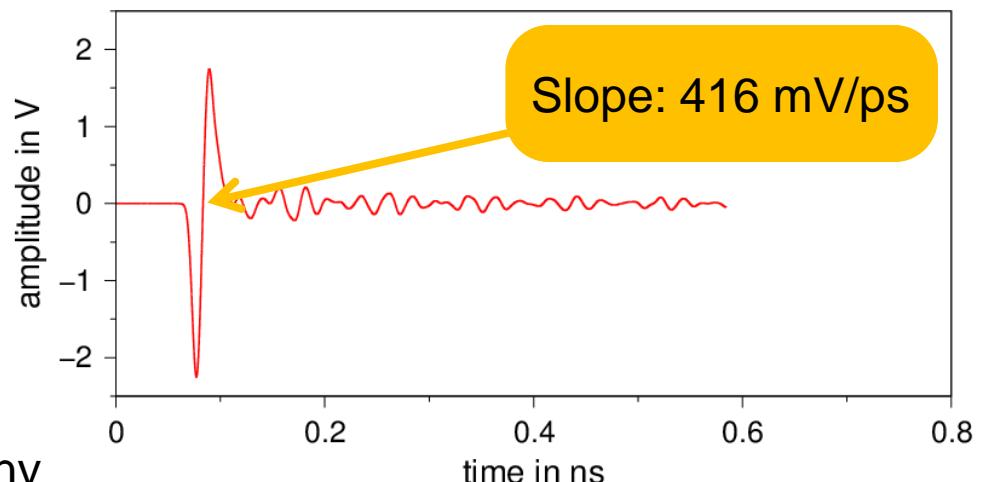
Simulation with 20 pC bunch charge



New 40 GHz Pickup



Design at TU Darmstadt, Germany



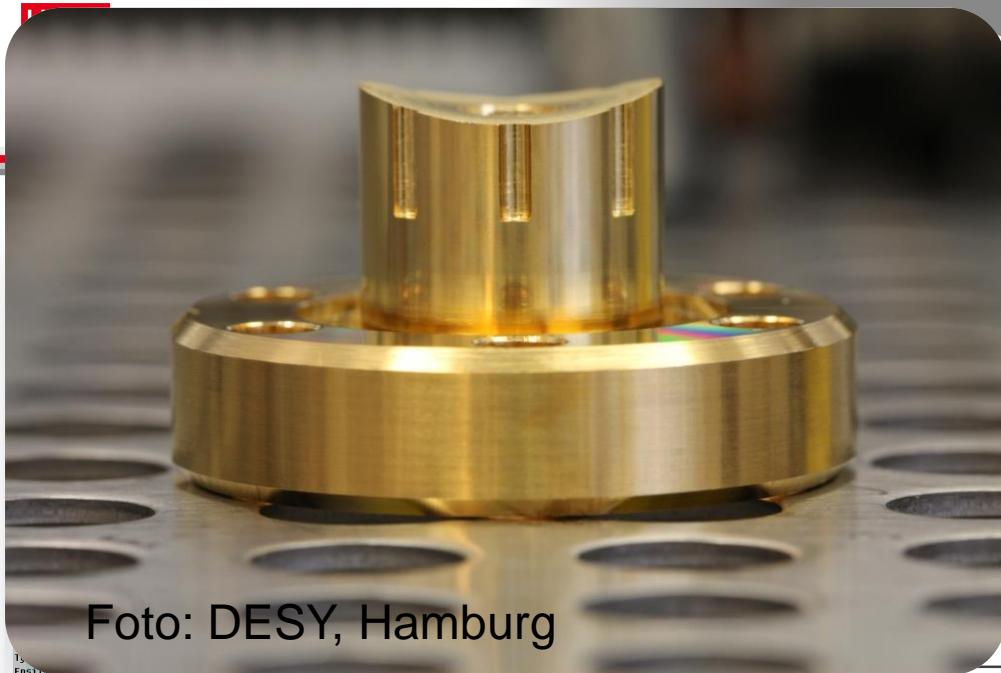
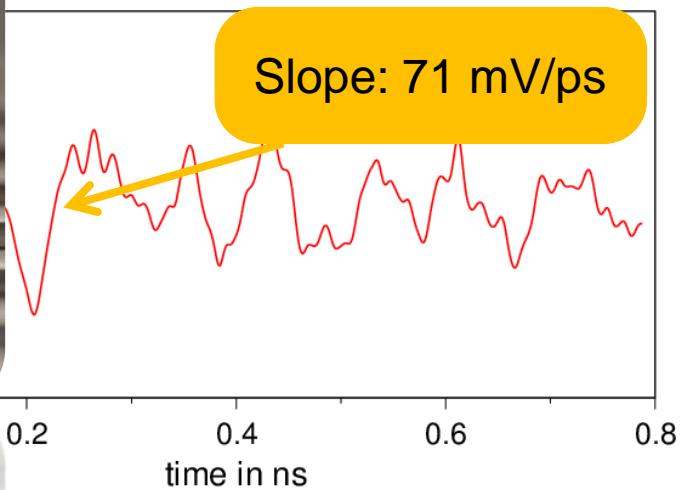


Foto: DESY, Hamburg

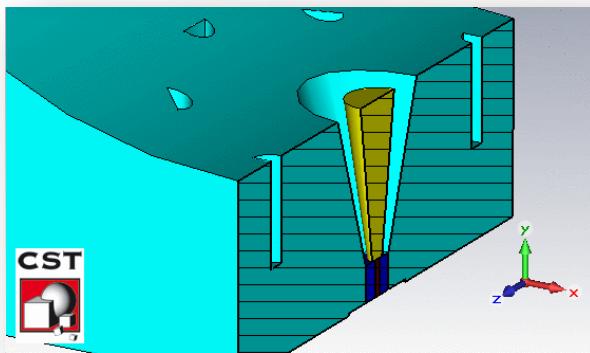


# Old and new Pickup

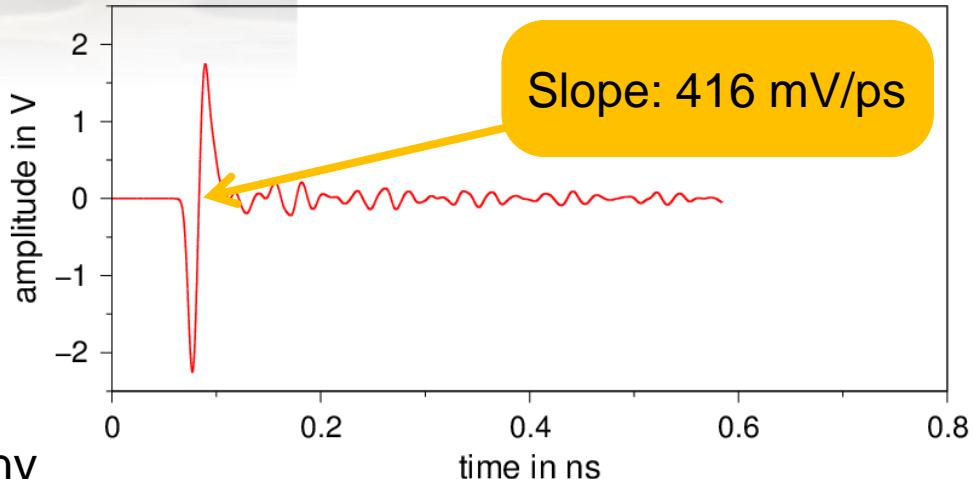
Response with 20 pC bunch charge

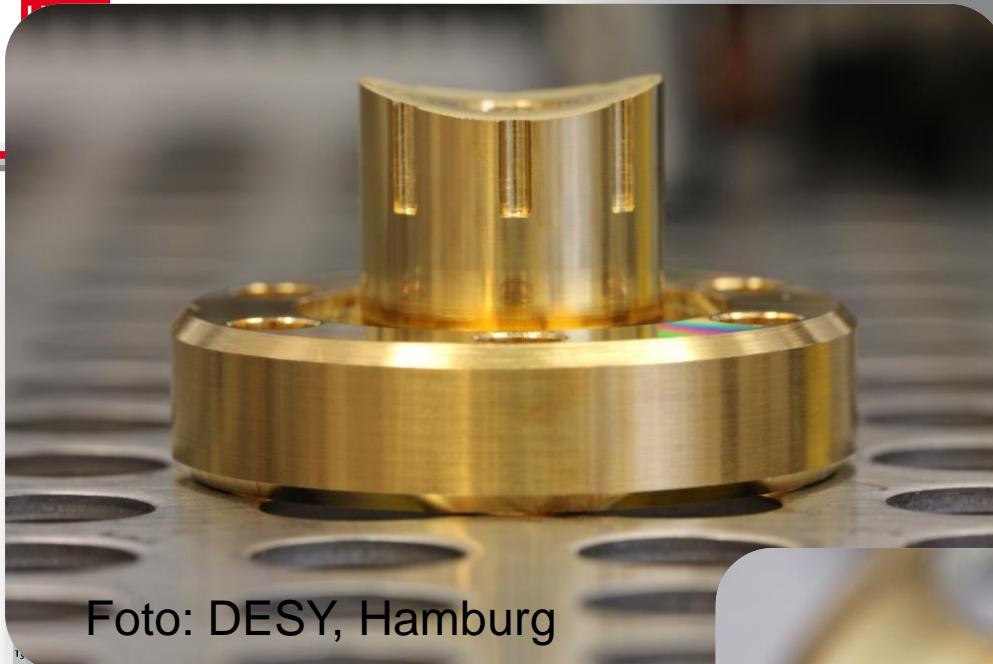


## New 40 GHz Pickup



Design at TU Darmstadt, Germany





# Old and new Pickup

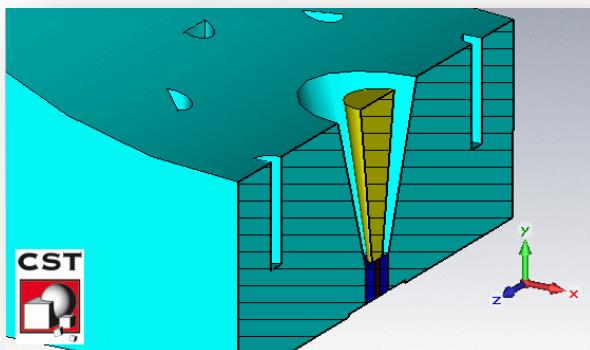
Old pickup response with 20 pC bunch charge



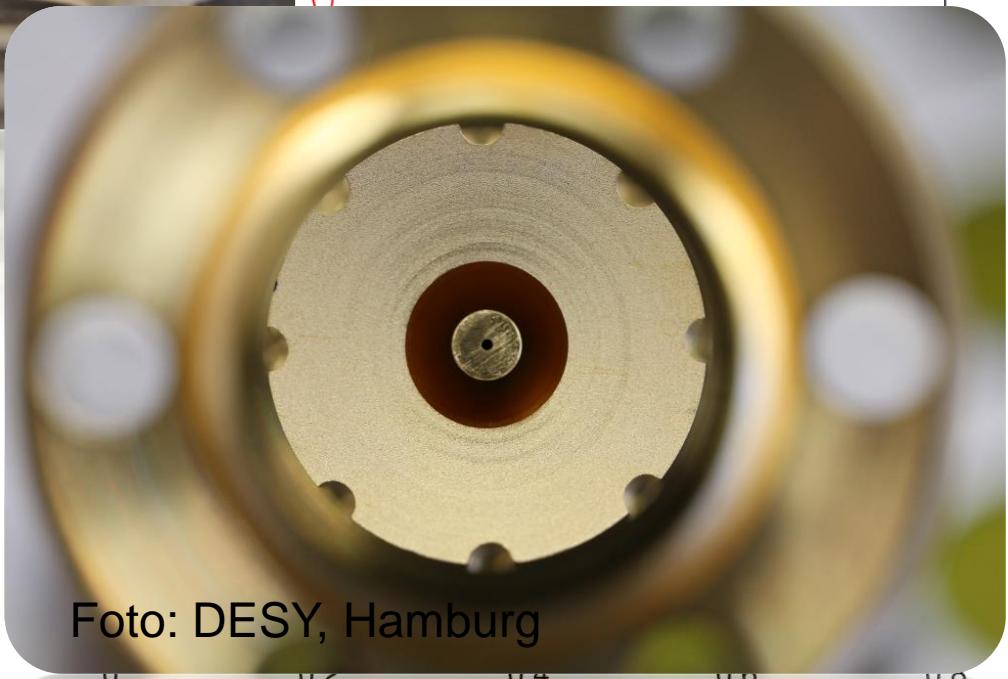
Foto: DESY, Hamburg



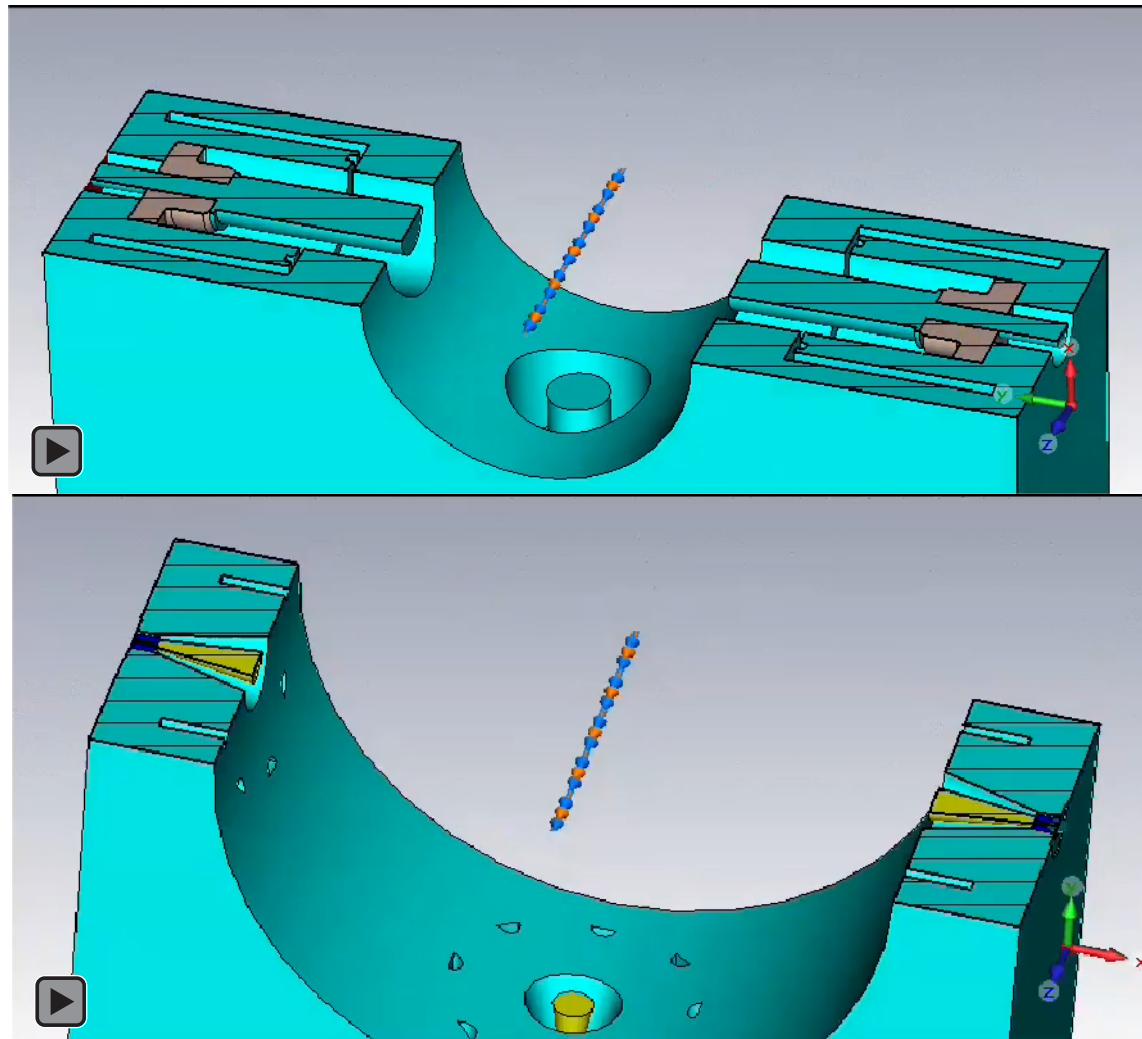
New 40 GHz Pickup



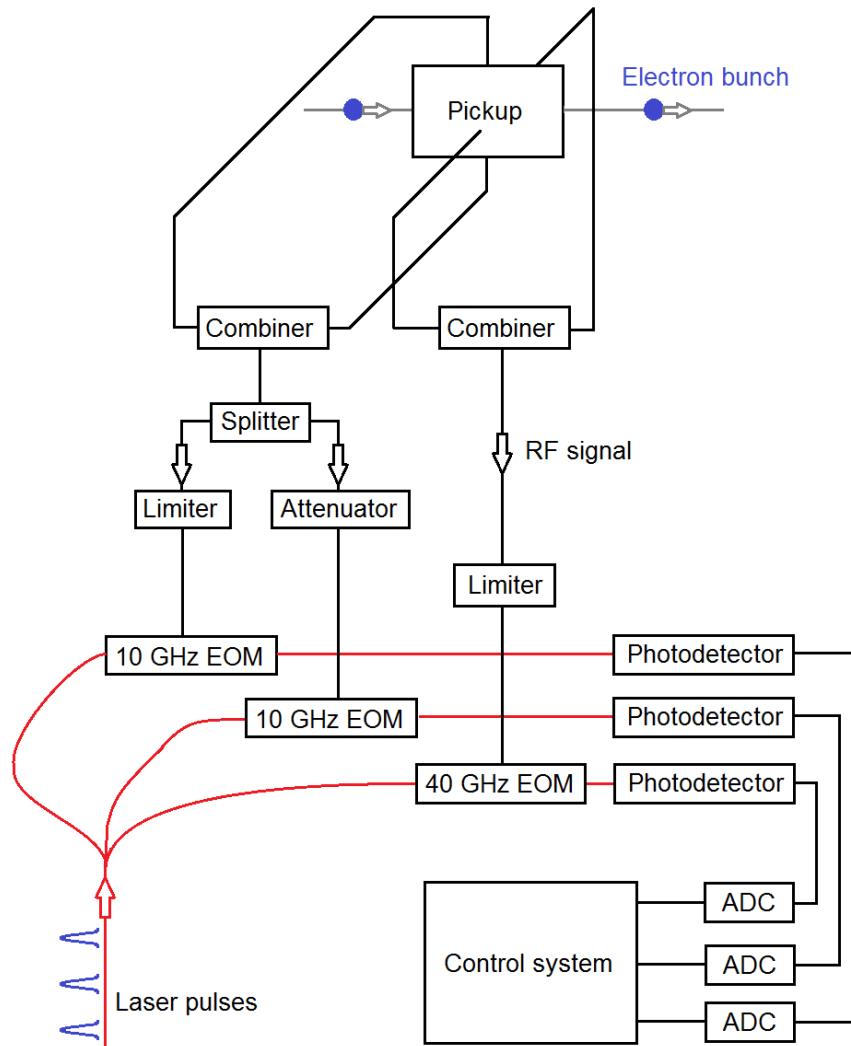
Design at TU Darmstadt, Germany



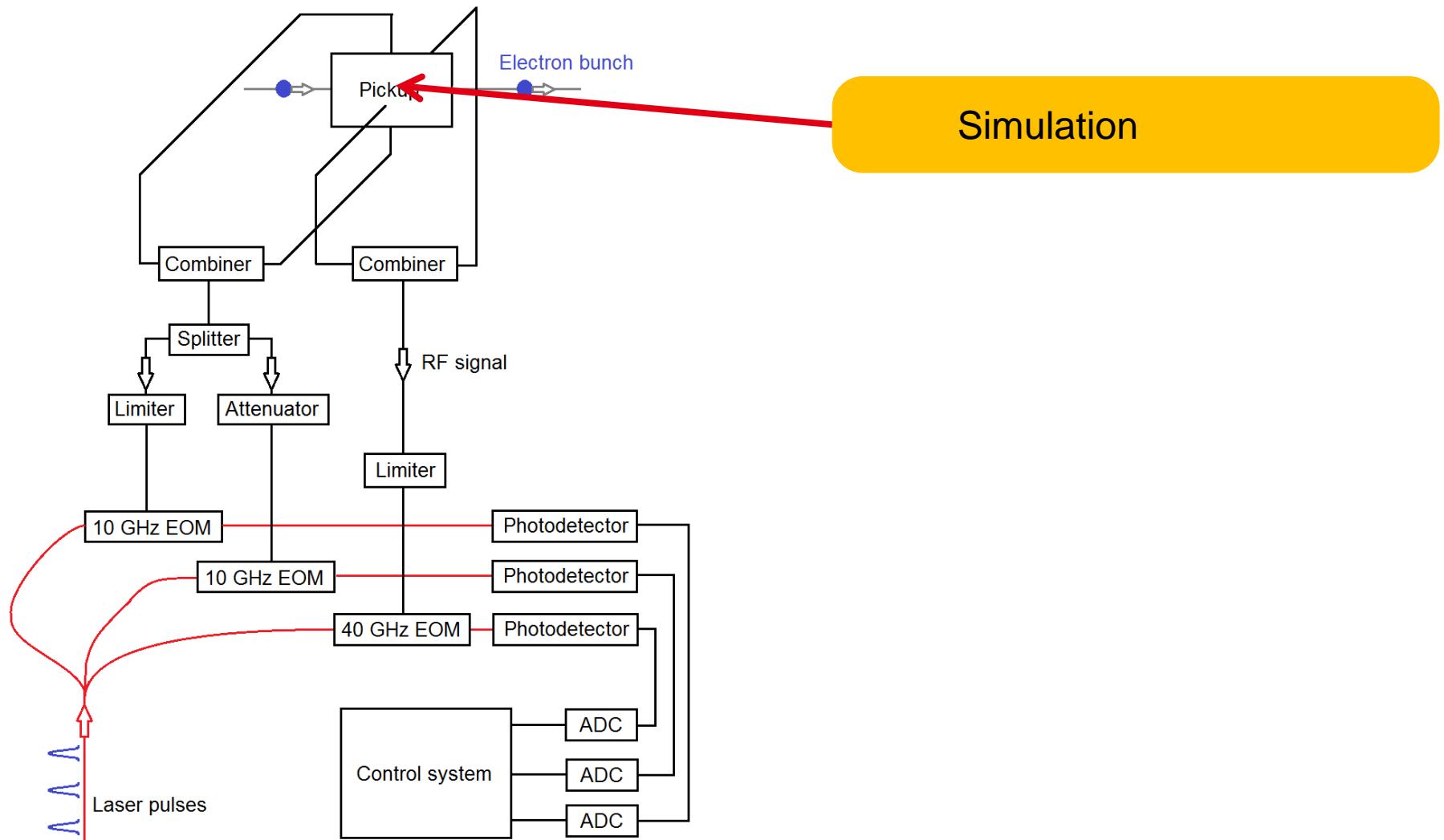
# Old and new Pickup



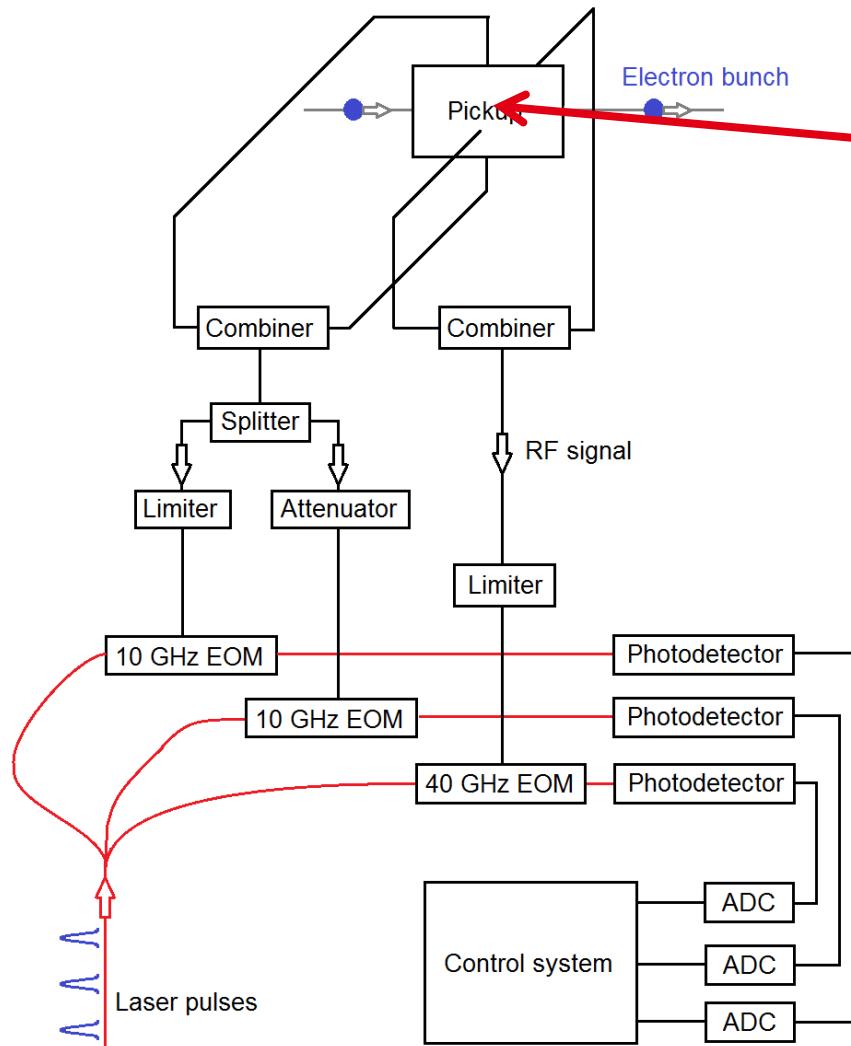
# RF calculation



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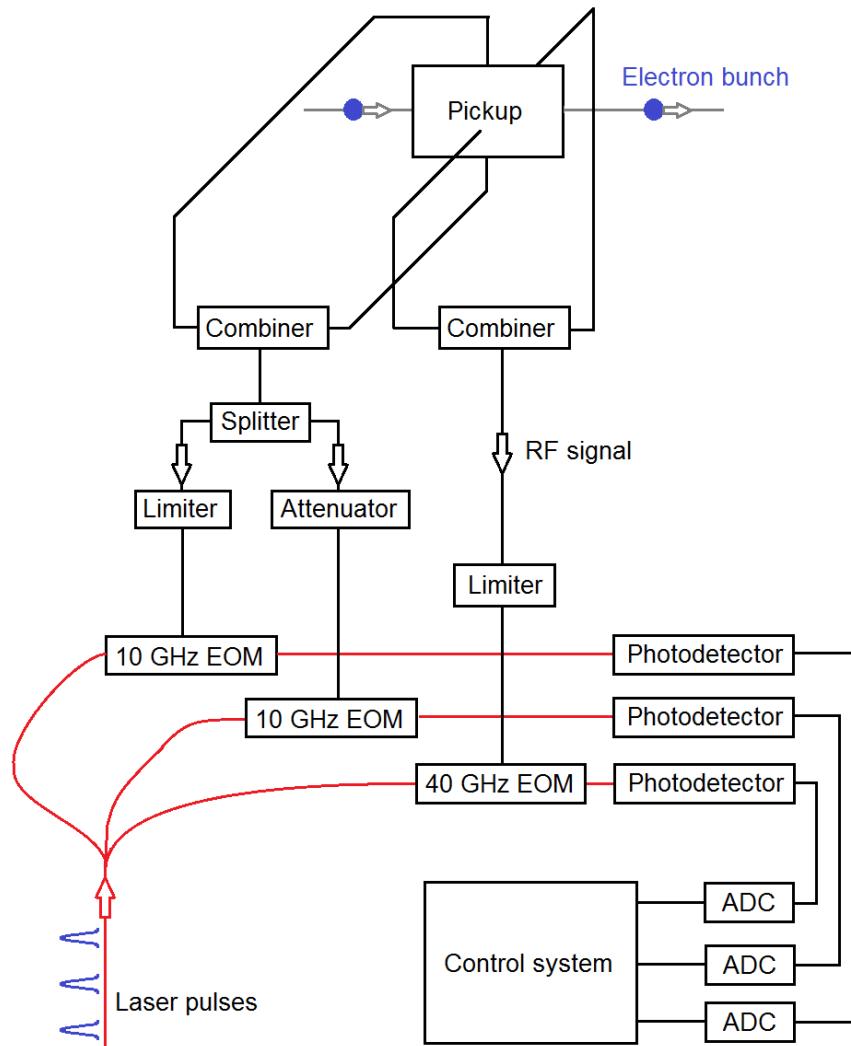
# RF calculation



Simulation

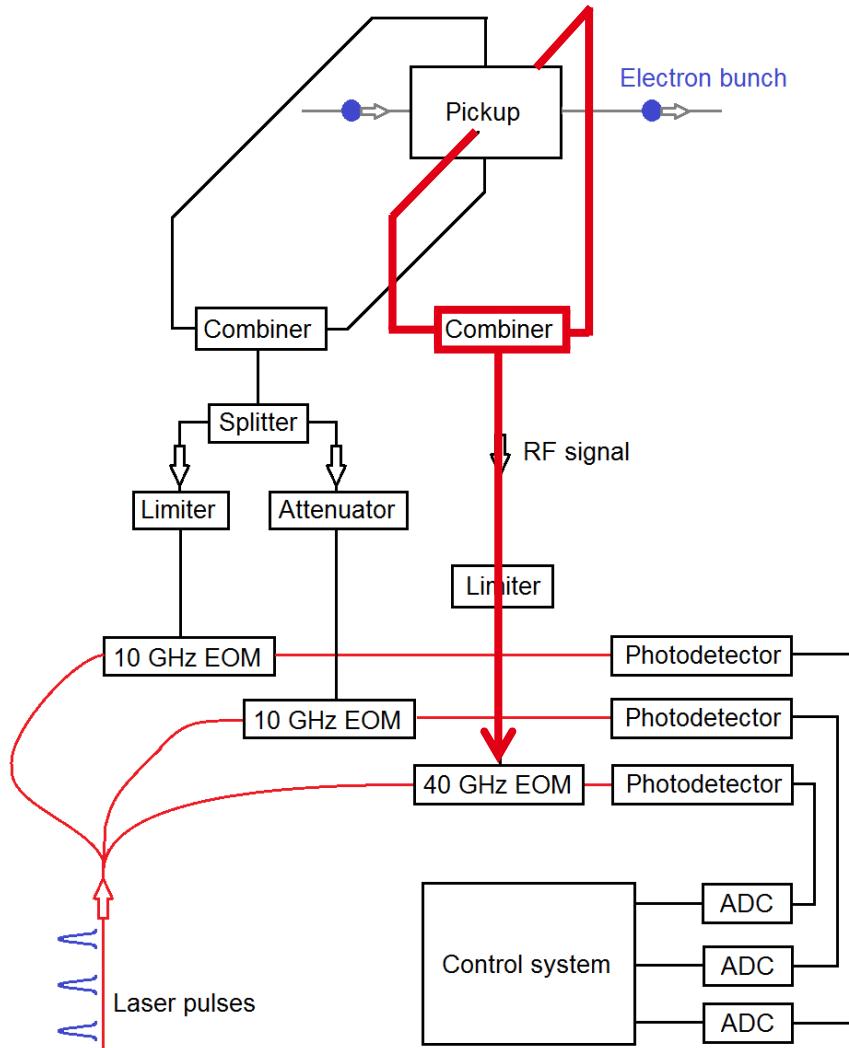
IBIC 2012 - MOPA46  
A. Angelovski et. al.

# RF calculation



Simulation

# RF calculation

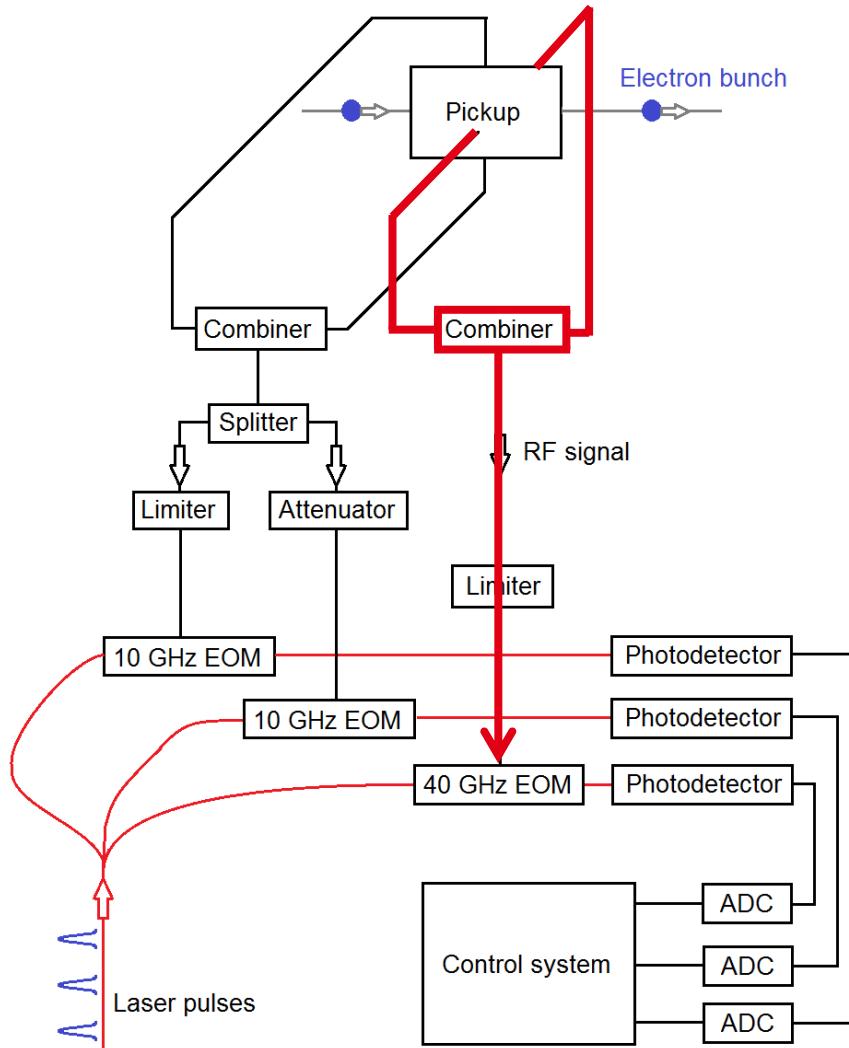


Simulation

Signal extrapolated by using S-parameters

- Cable
- Combiner

# RF calculation



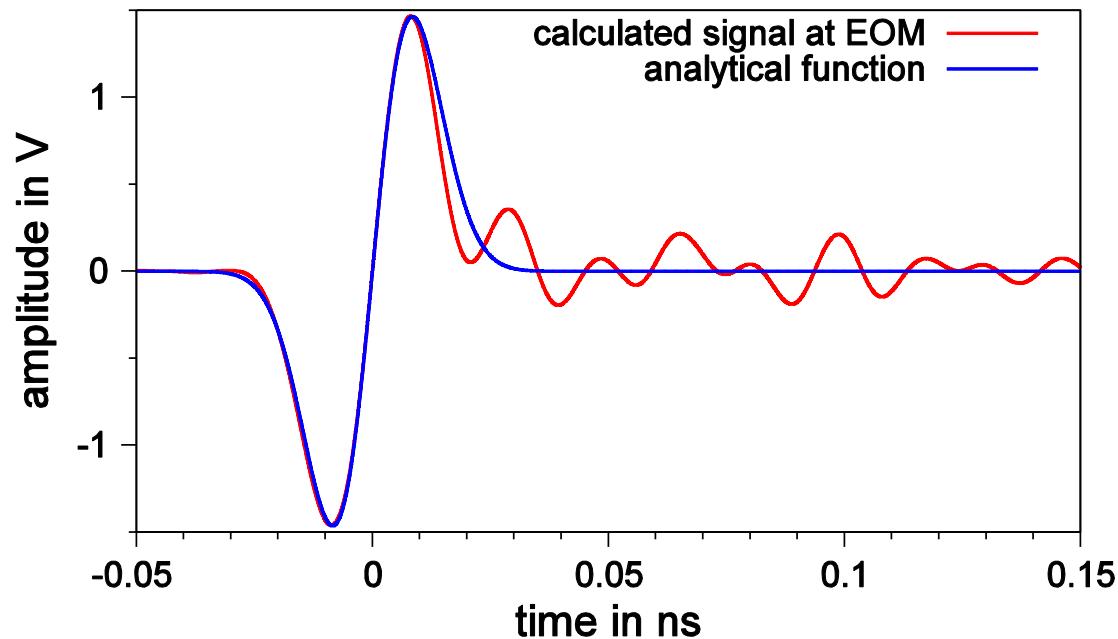
Simulation

Signal extrapolated by using S-parameters

- Cable
- Combiner

IBIC 2012 - MOPA43  
A. Penirschke et. al.

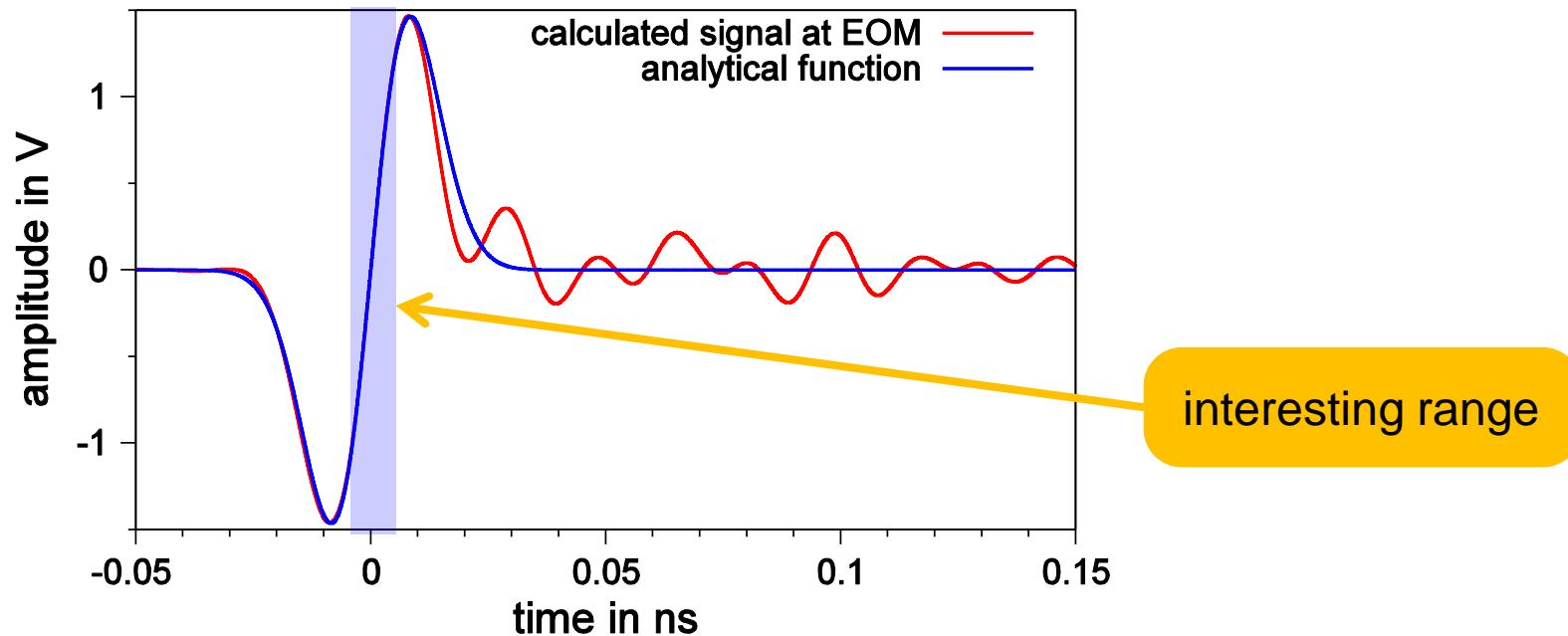
## Signal at the 40 GHz EOM



$$U(t) = t S e^{-\left(\frac{t S}{A e^{0.5}}\right)^2}$$

S Slope: 286 mV/ps  
A Amplitude: 1.463 V

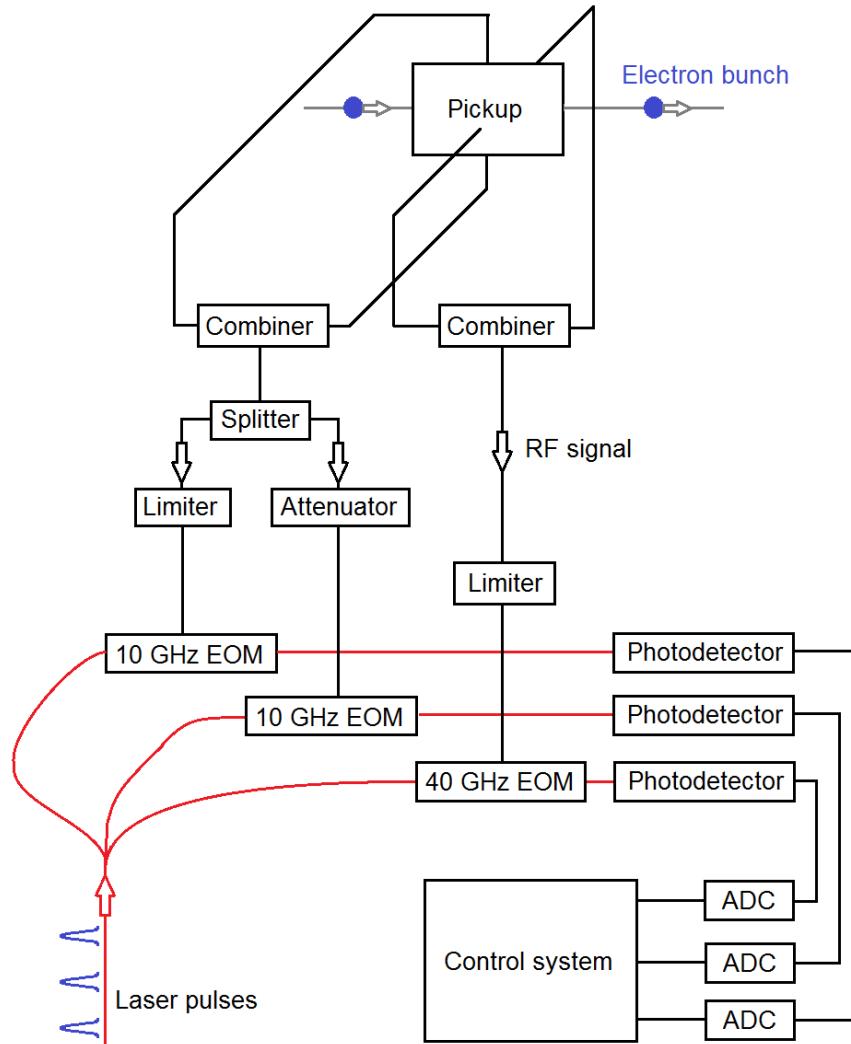
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# Electro Optical Modulator (EOM)

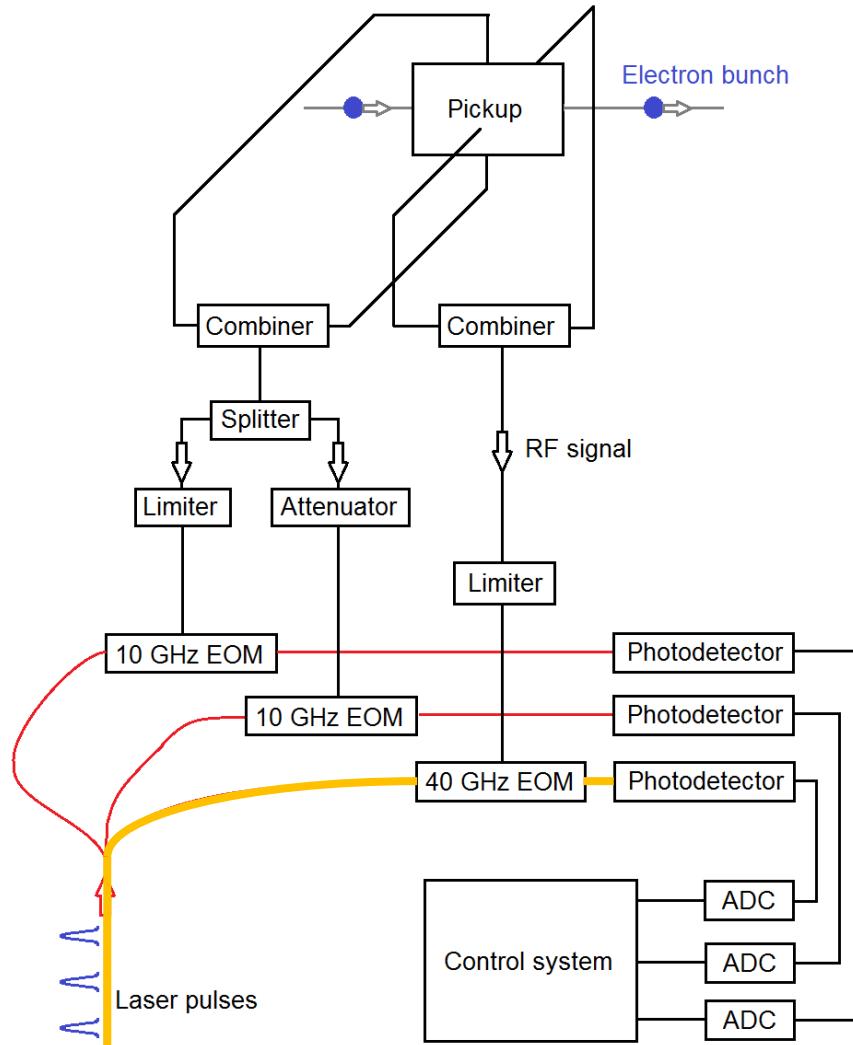


Simulation

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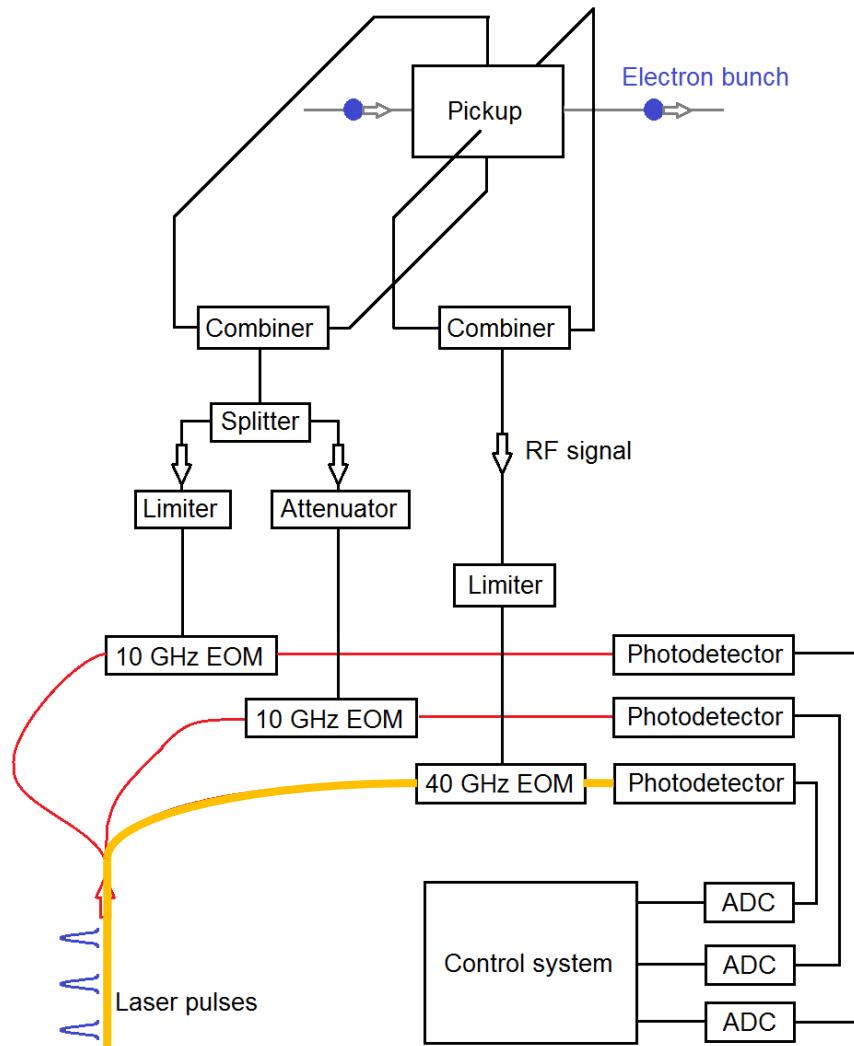


Simulation

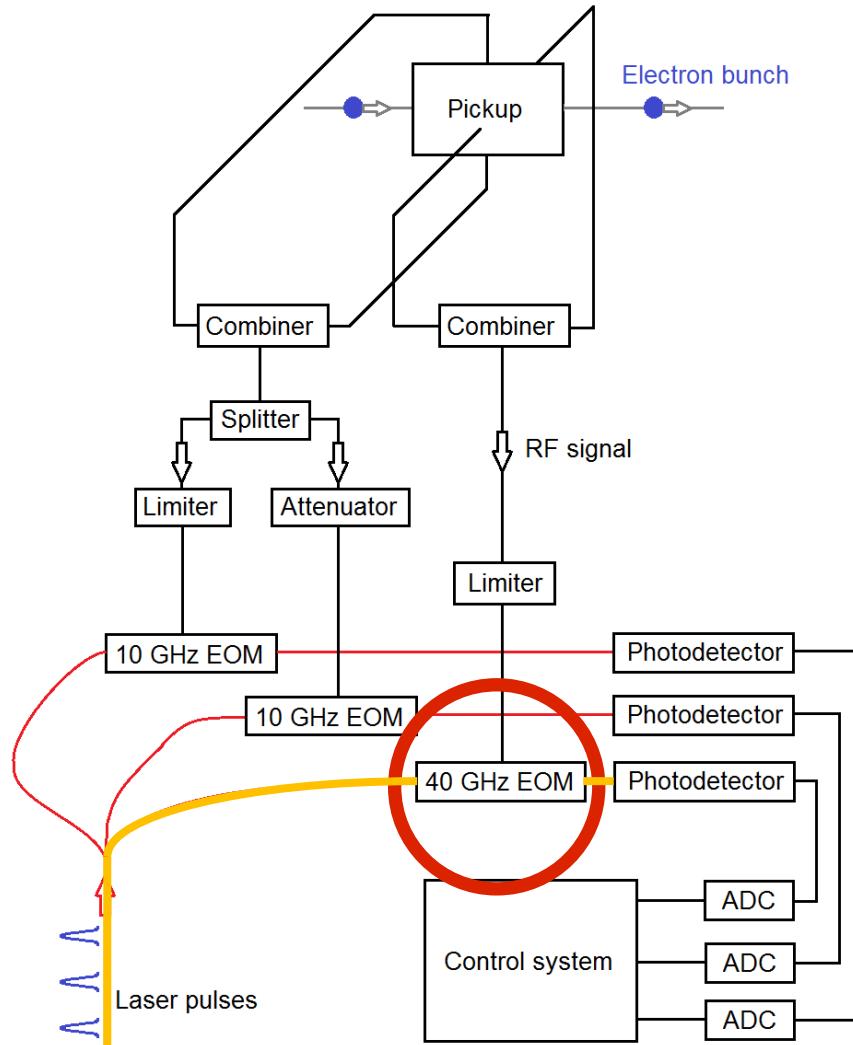
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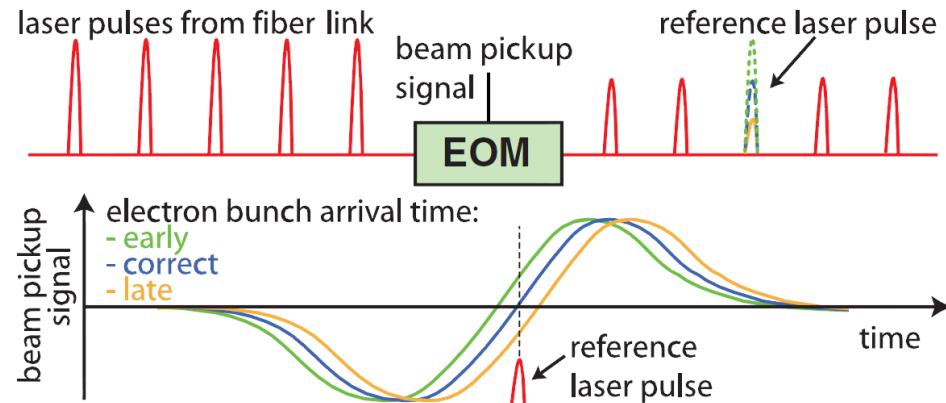
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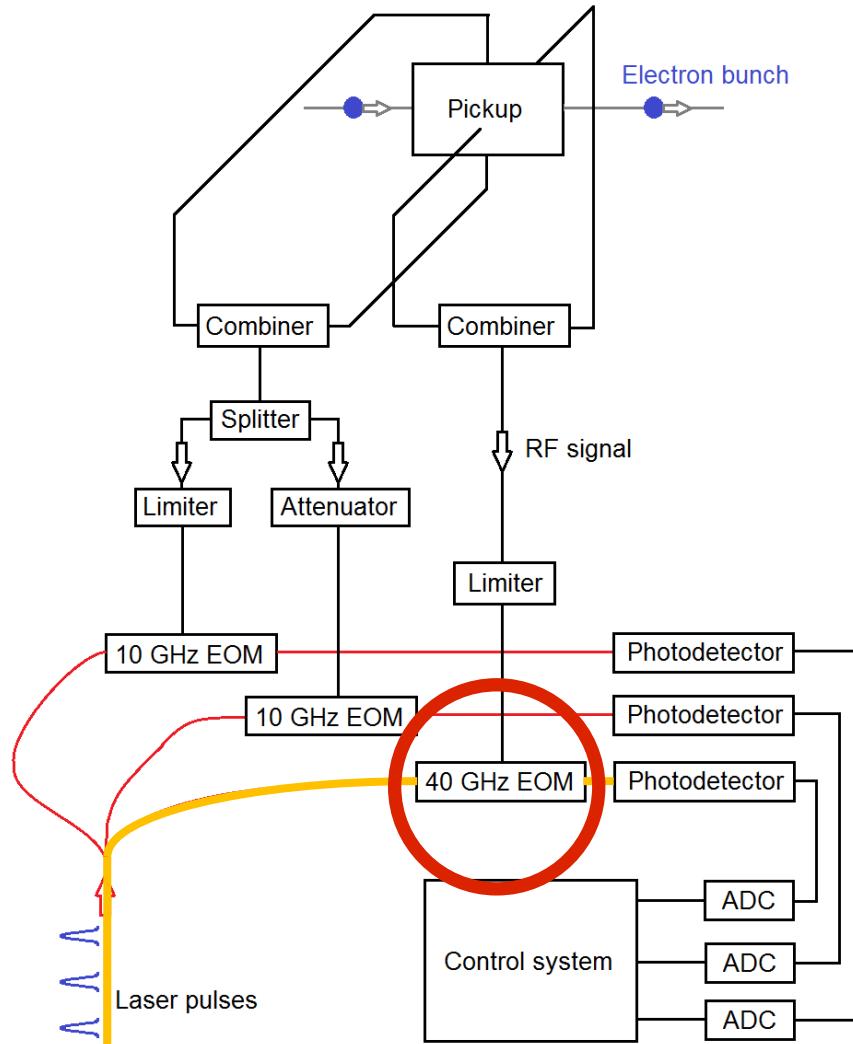


Principle of measurement

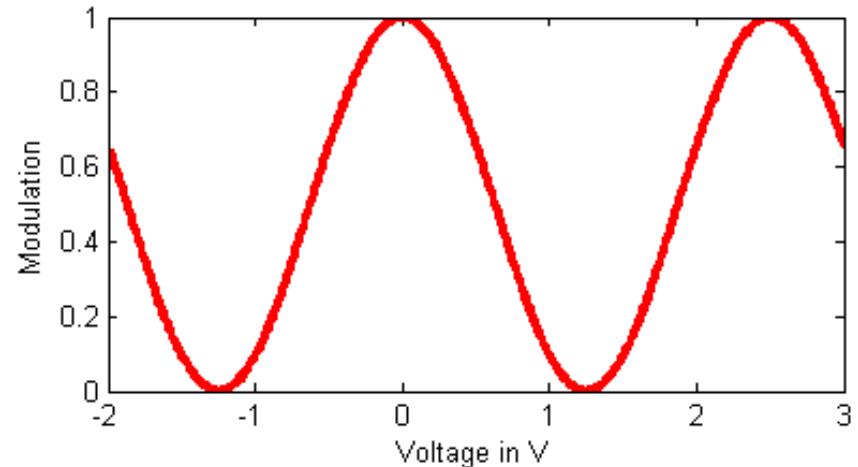


Courtesy by F. Löhl

# Electro Optical Modulator (EOM)



Modulation of the laser pulse



$$M = \frac{I_{out}}{I_{in}} = \frac{1}{2} + \frac{1}{2} \cos \left( \delta_0 + \frac{\pi}{U_\pi} U(t_m) \right)$$

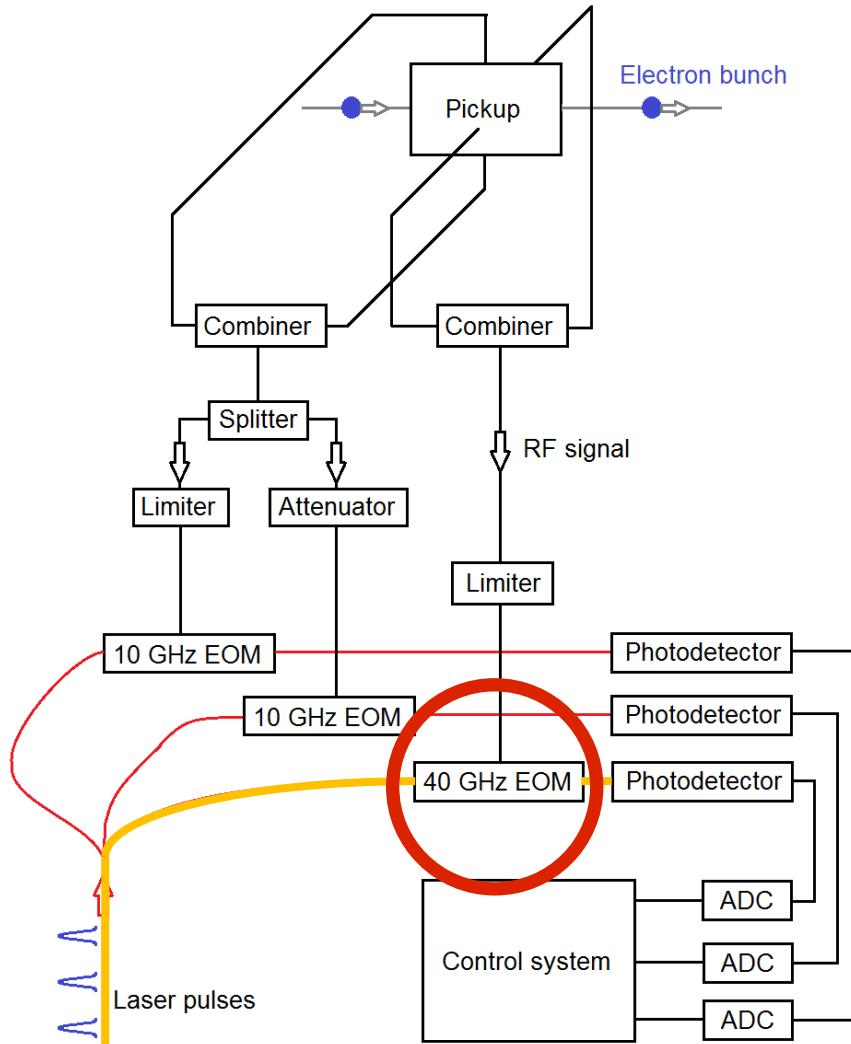
$M$  = Modulation

$I$  = Laser amplitude

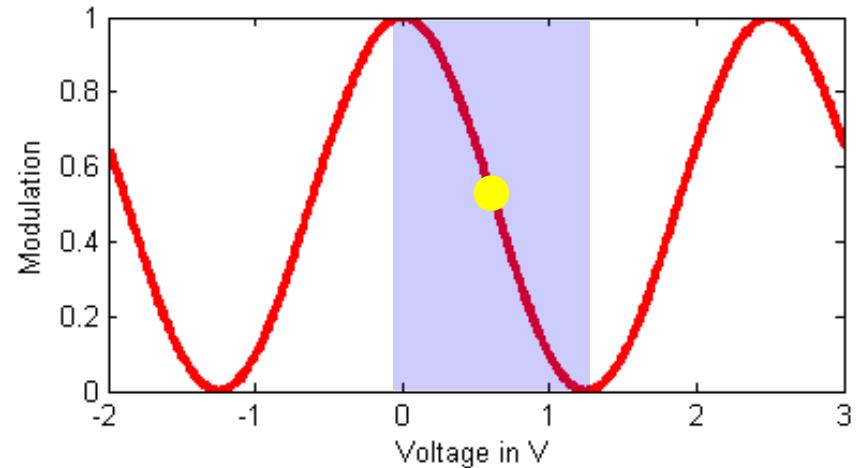
$\delta_0$  = intrinsic operation point

$U_\pi$  = Voltage to change  $M$  from 0 to 1

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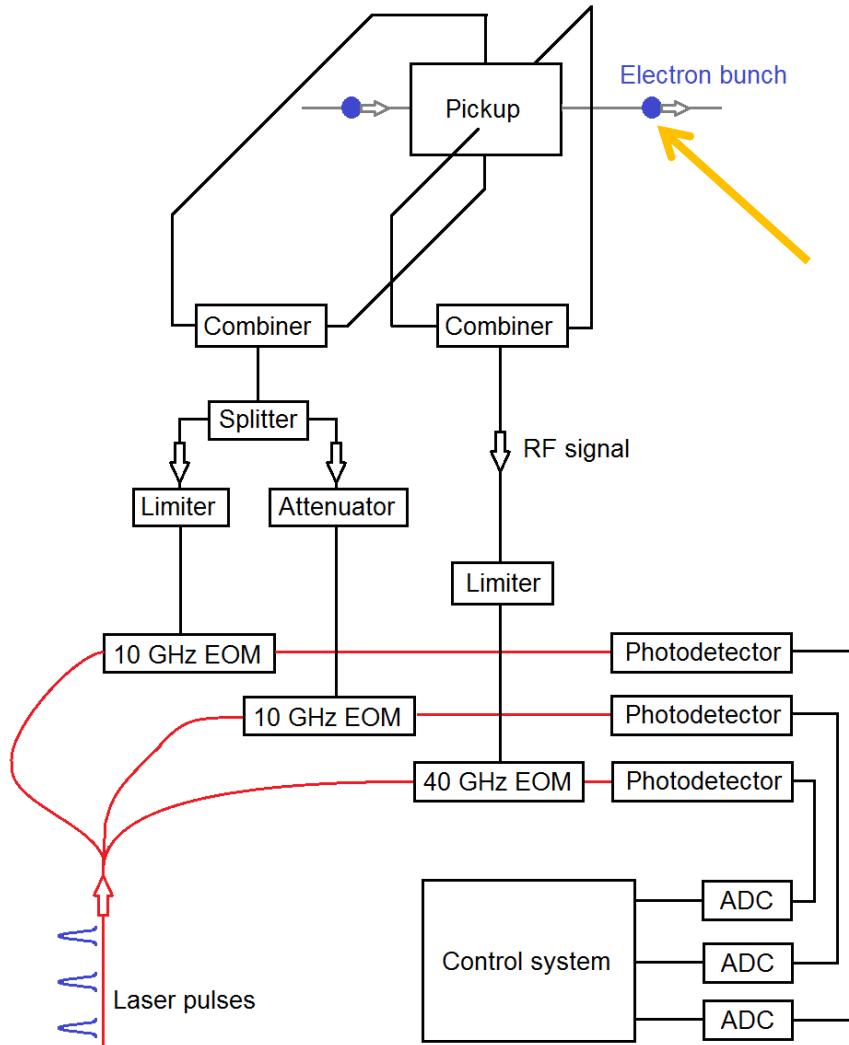
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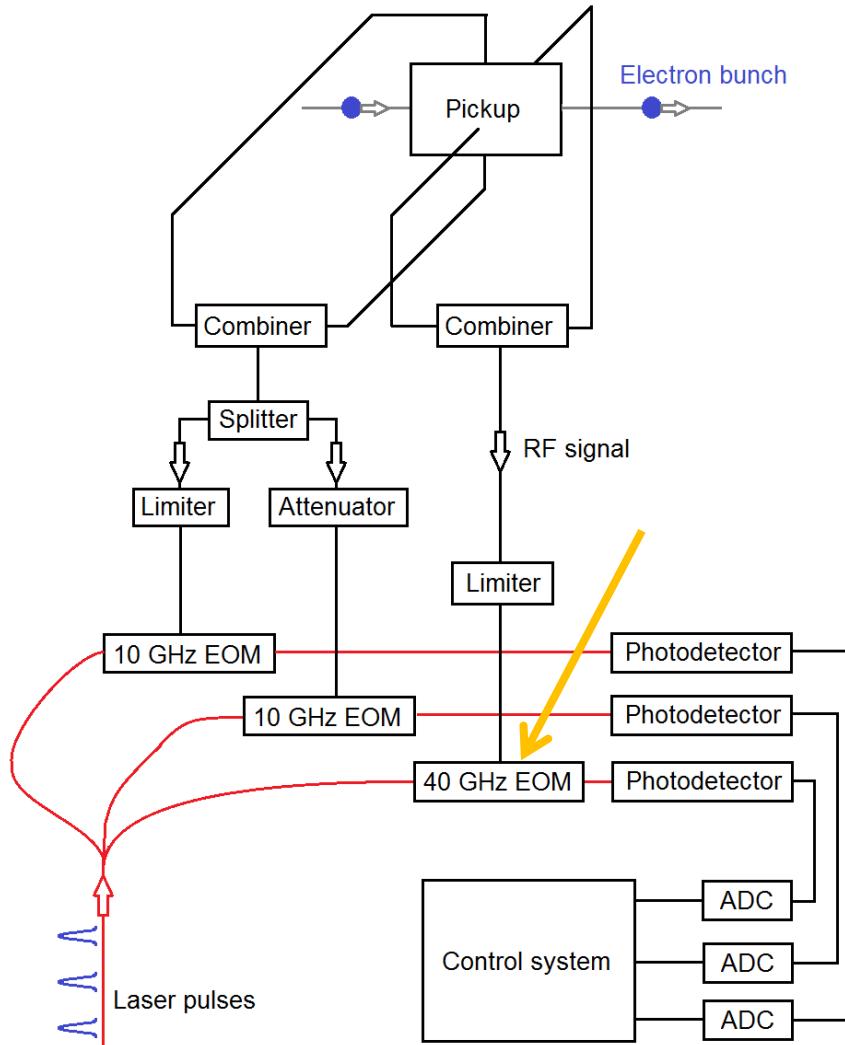
# Monte Carlo Simulation



Influence of different jitter sources  
on the arrival time measurement

Parameter	Assumed RMS values
Bunch charge	1 %

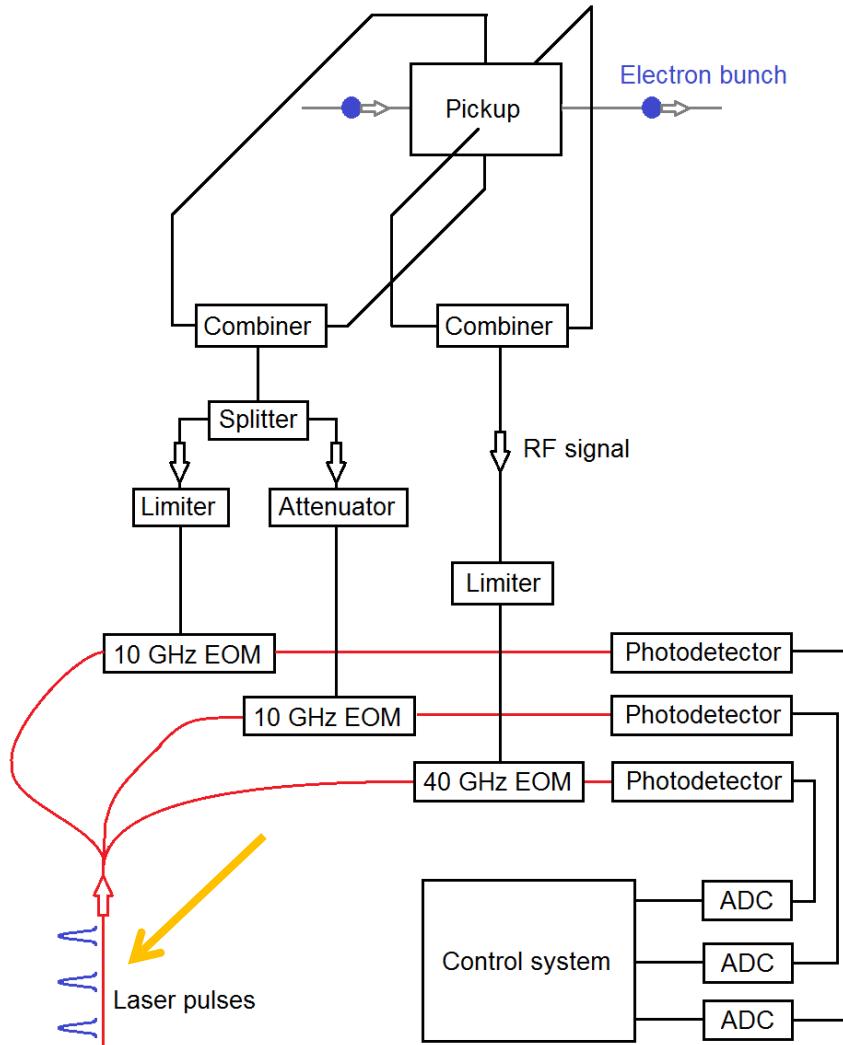
# Monte Carlo Simulation



Influence of different jitter sources  
on the arrival time measurement

Parameter	Assumed RMS values
Bunch charge	1 %
Bias voltage	0.5 mV
RF voltage	0.5 mV

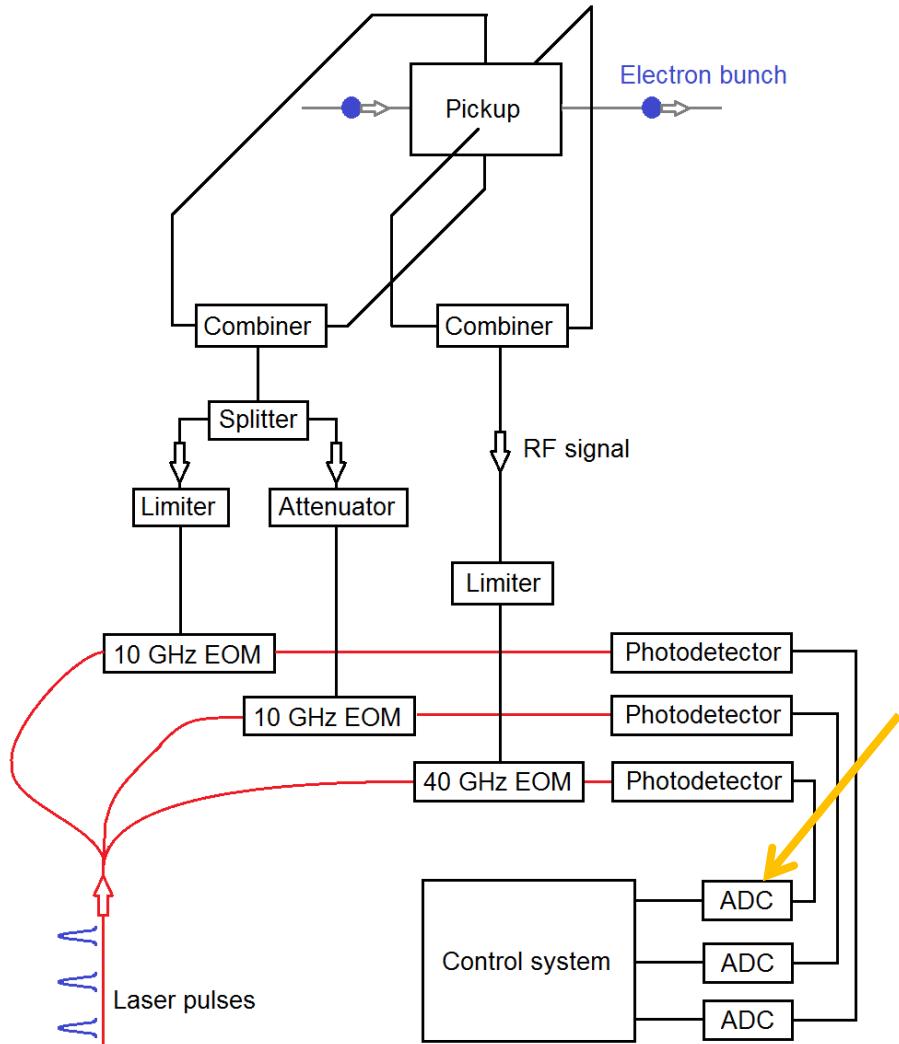
# Monte Carlo Simulation



Influence of different jitter sources  
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Parameter	Assumed RMS values
Bunch charge	1 %
Bias voltage	0.5 mV
RF voltage	0.5 mV
Laser amplitude	0.35 %
Laser timing	2.5 fs

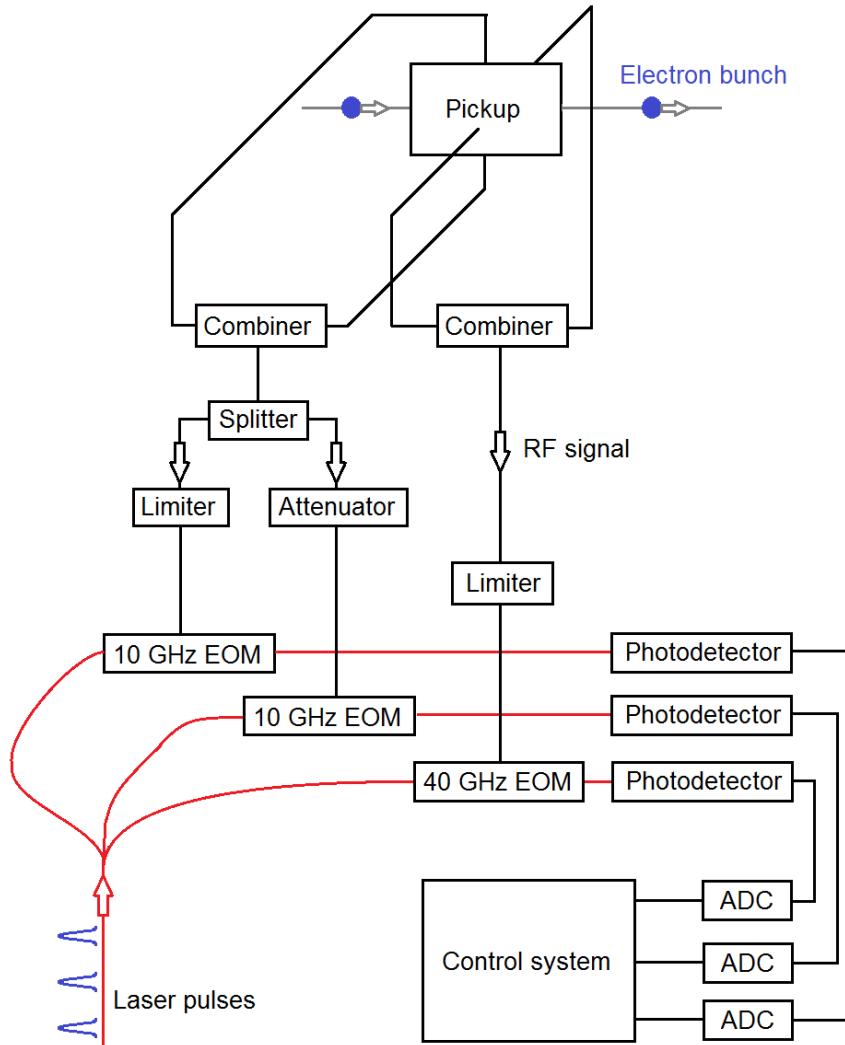
# Monte Carlo Simulation



Influence of different jitter sources  
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Parameter	Assumed RMS values
Bunch charge	1 %
Bias voltage	0.5 mV
RF voltage	0.5 mV
Laser amplitude	0.35 %
Laser timing	2.5 fs
ADC channel (16bit)	20

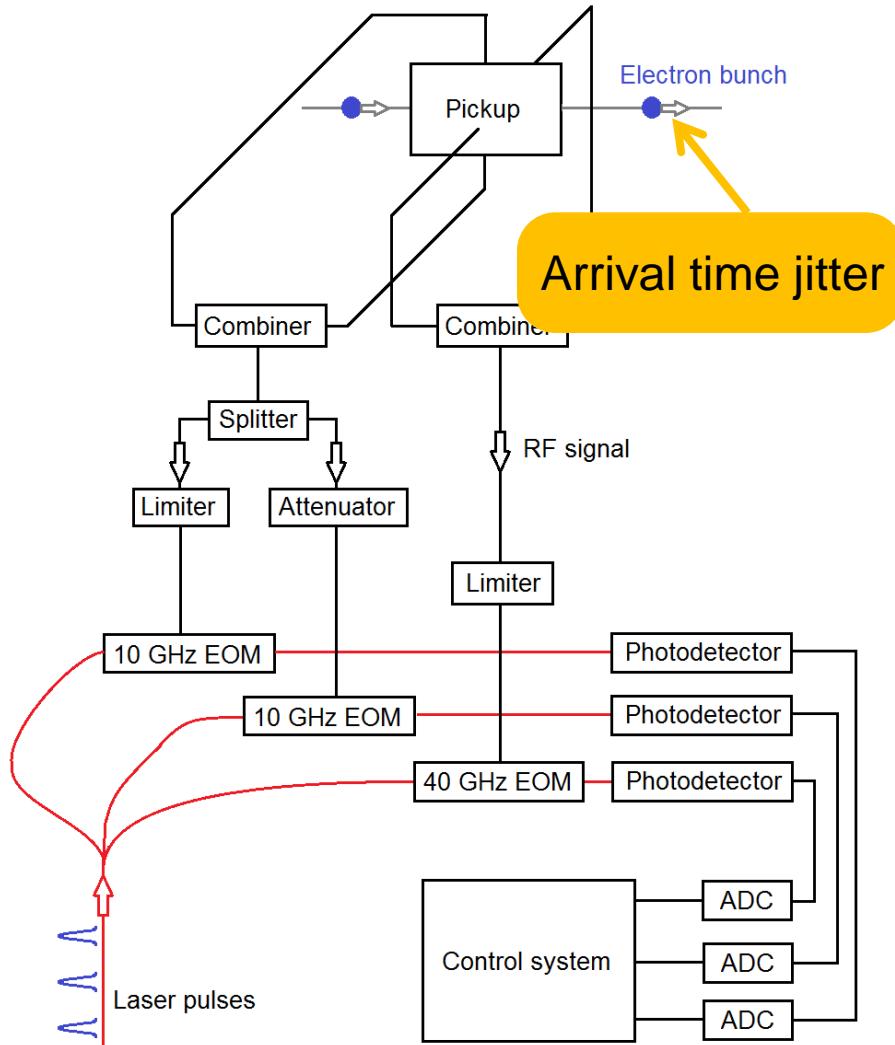
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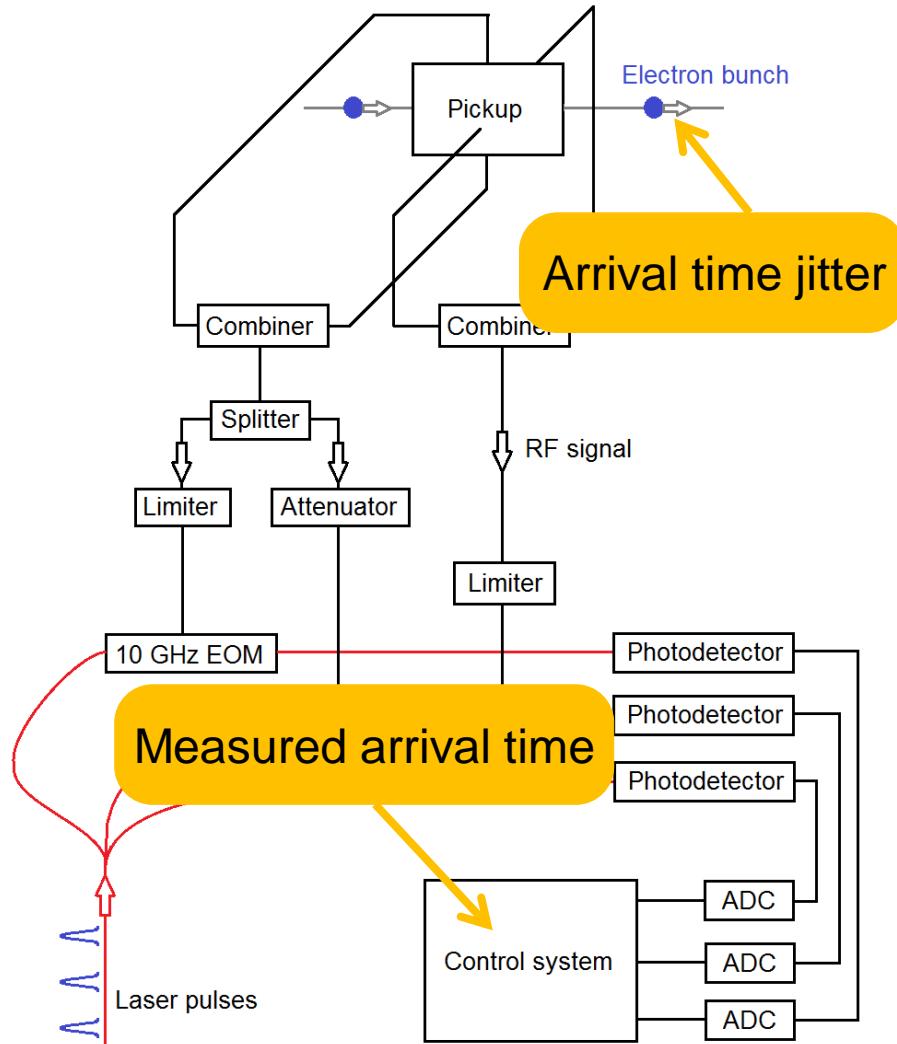
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## Monte Carlo Simulation

\*Normaly distributed

## Monte Carlo Simulation

### 1. Random set of the Parameter\*

\*Normaly distributed

## Monte Carlo Simulation

1. Random set of the Parameter\*
2. Also a random value for the arrival time of the bunch\*

\*Normaly distributed

## Monte Carlo Simulation

1. Random set of the Parameter\*
2. Also a random value for the arrival time of the bunch\*
3. Calculation of the measured arrival time

\*Normaly distributed

## Monte Carlo Simulation

1. Random set of the Parameter\*
2. Also a random value for the arrival time of the bunch\*
3. Calculation of the measured arrival time
4. Compare

\*Normaly distributed

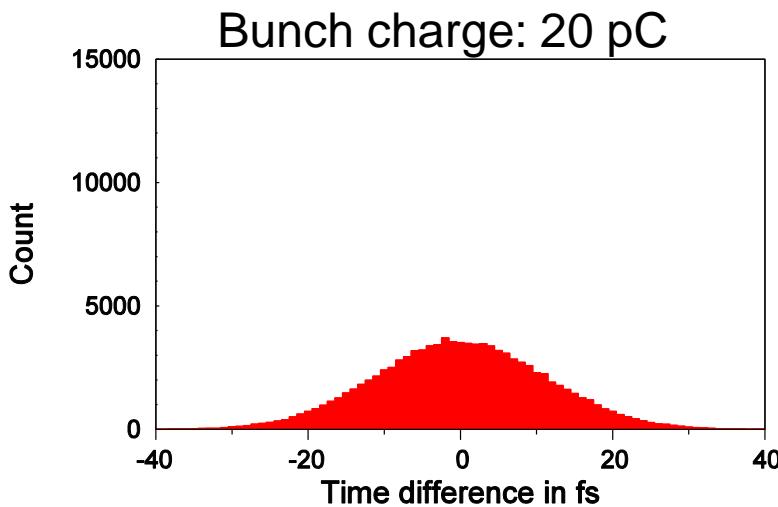
## Monte Carlo Simulation

- 
1. Random set of the Parameter\*
  2. Also a random value for the arrival time of the bunch\*
  3. Calculation of the measured arrival time
  4. Compare
  5. Repeat this 100.000 times

\*Normaly distributed

## Monte Carlo Simulation

1. Random set of the Parameter\*
2. Also a random value for the arrival time of the bunch\*
3. Calculation of the measured arrival time
4. Compare
5. Repeat this 100.000 times

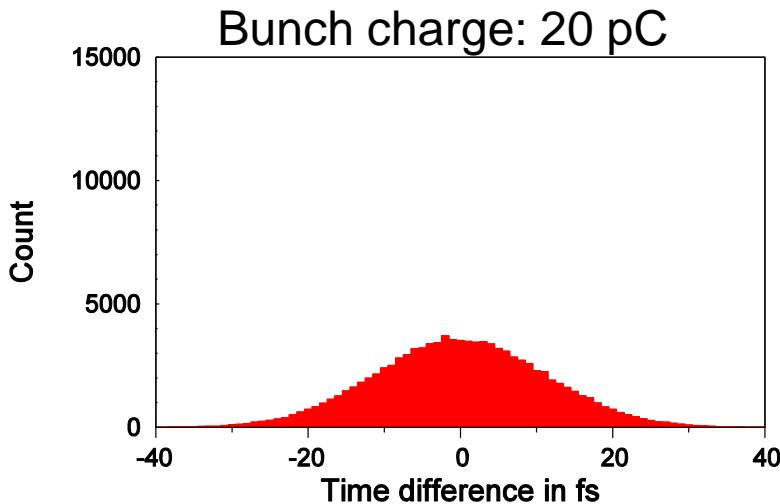


Simulated measurement accuracy = 11fs RMS

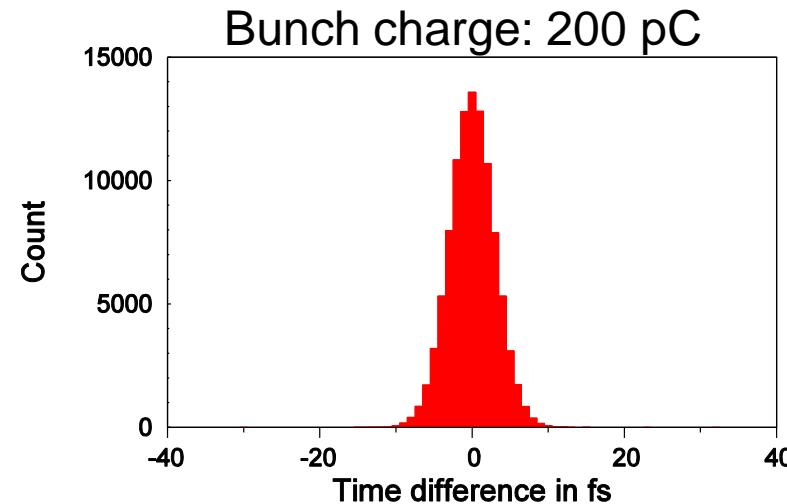
\*Normaly distributed

## Monte Carlo Simulation

1. Random set of the Parameter\*
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3. Calculation of the measured arrival time
4. Compare
5. Repeat this 100.000 times



Simulated measurement accuracy = 11fs RMS



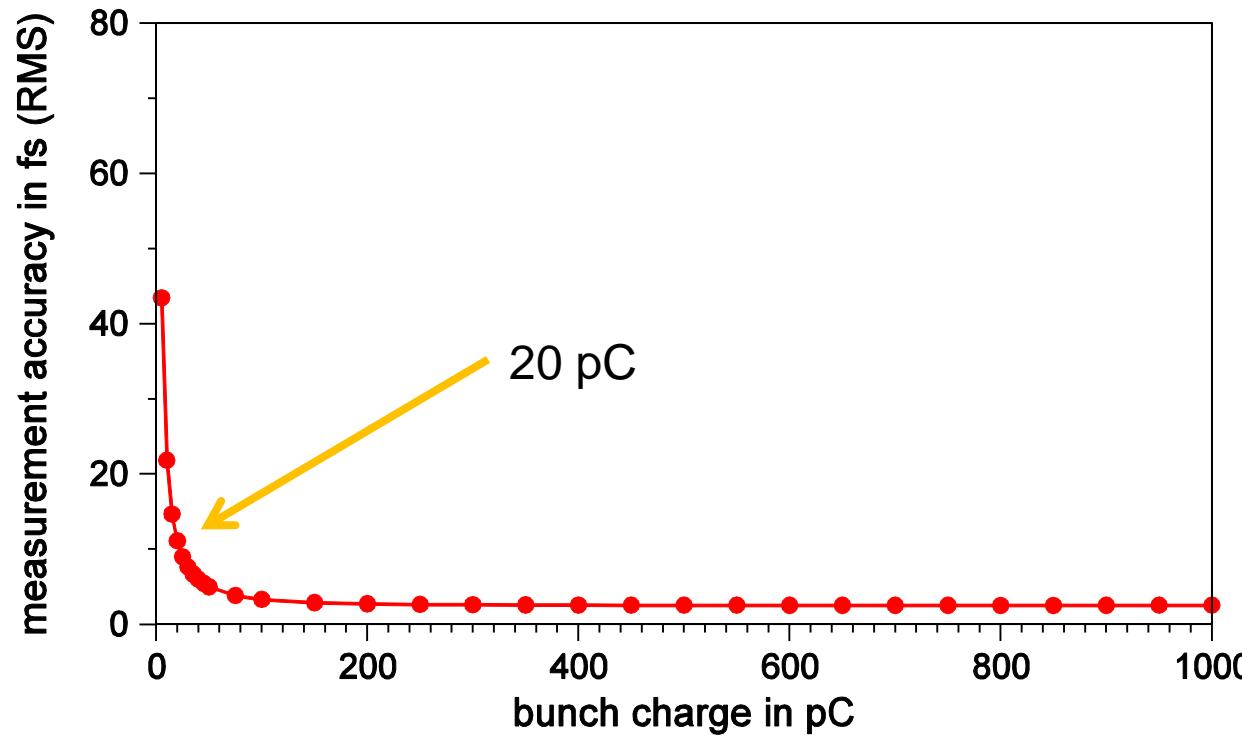
Simulated measurement accuracy = 3 fs RMS

\*Normaly distributed

# Results

Simulated timing resolution with different bunch charges

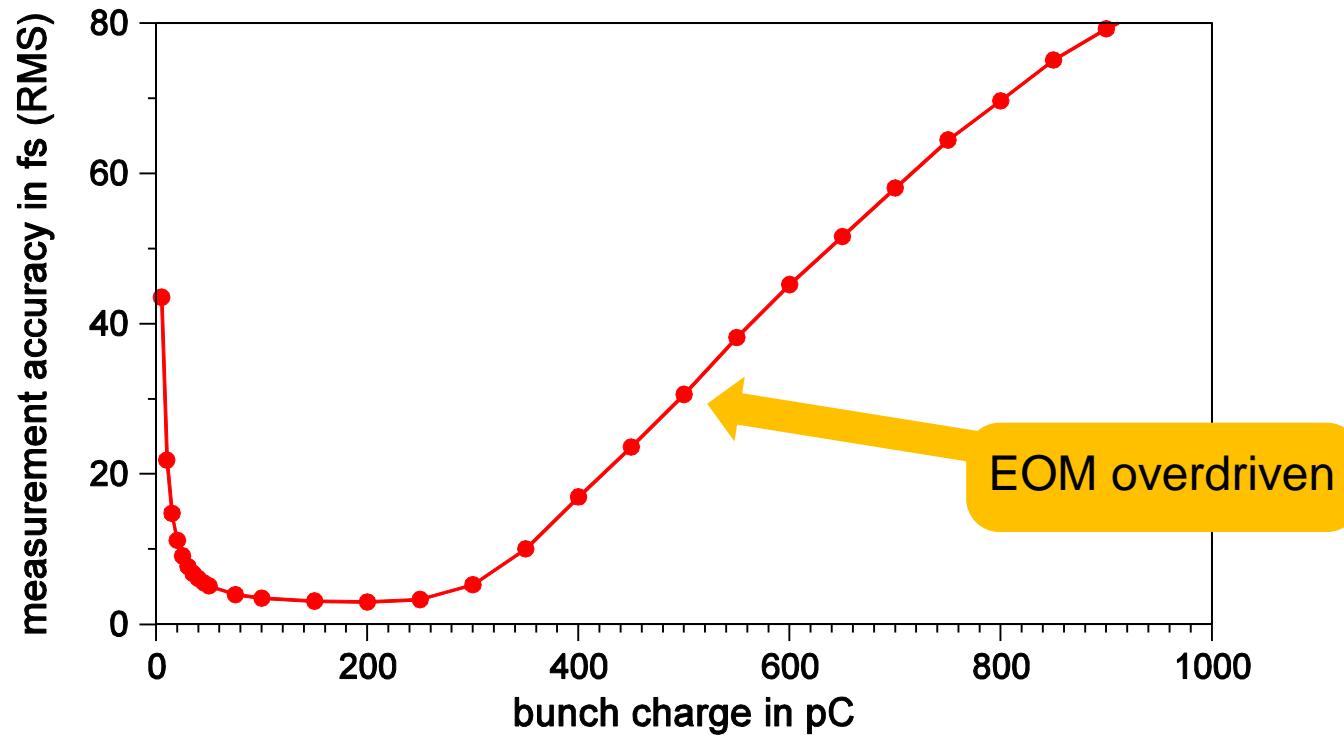
Random value for the arrival time of the bunch: 25 fs RMS



# Results

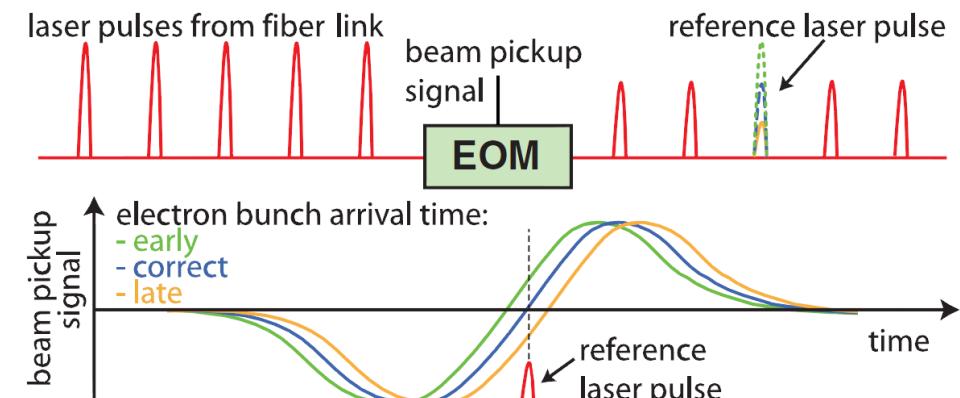
Simulated timing resolution with different bunch charges

Random value for the arrival time of the bunch: 100 fs RMS



# Results

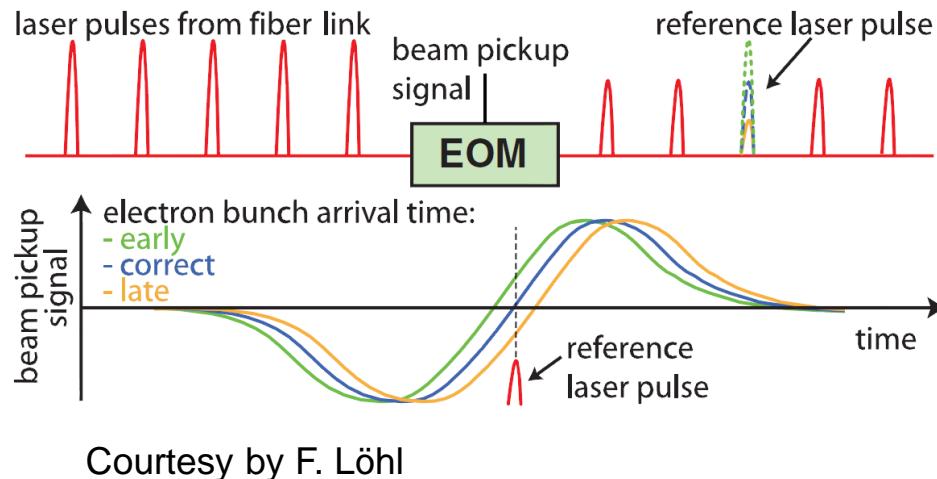
## Back to principle of measurement



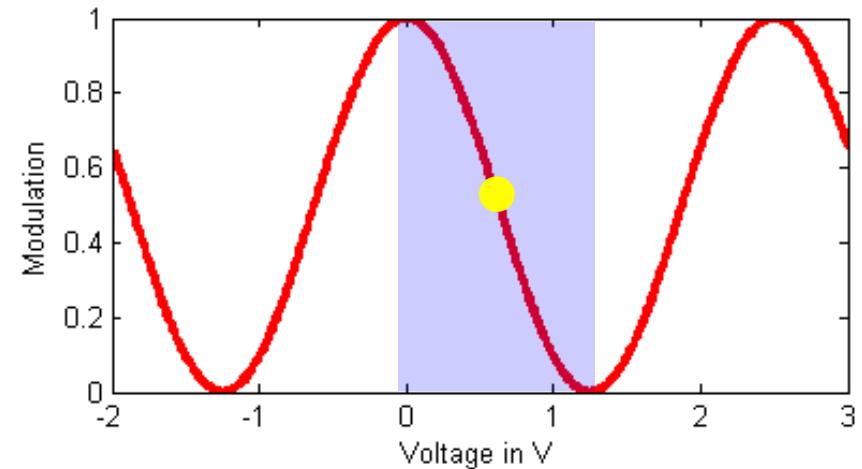
Courtesy by F. Löhl

# Results

## Back to principle of measurement



## Modulation of the laser pulse



$$M = \frac{I_{out}}{I_{in}} = \frac{1}{2} + \frac{1}{2} \cos \left( \delta_0 + \frac{\pi}{U_\pi} U(t_m) \right)$$

$M$  = Modulation

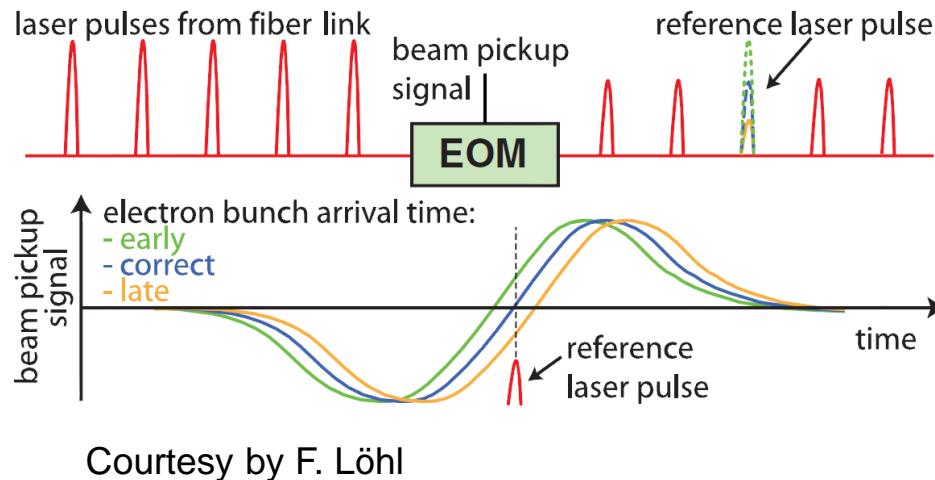
$I$  = Laser amplitude

$\delta_0$  = intrinsic operation point

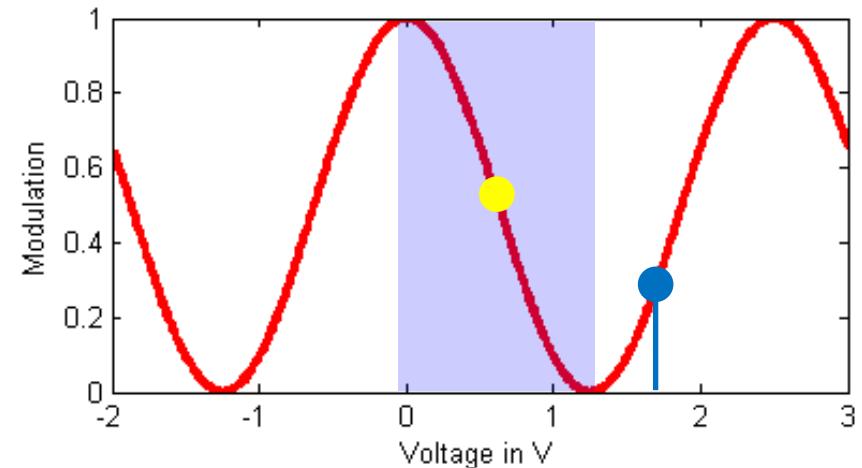
$U_\pi$  = Voltage to change  $M$  from 0 to 1

# Results

## Back to principle of measurement



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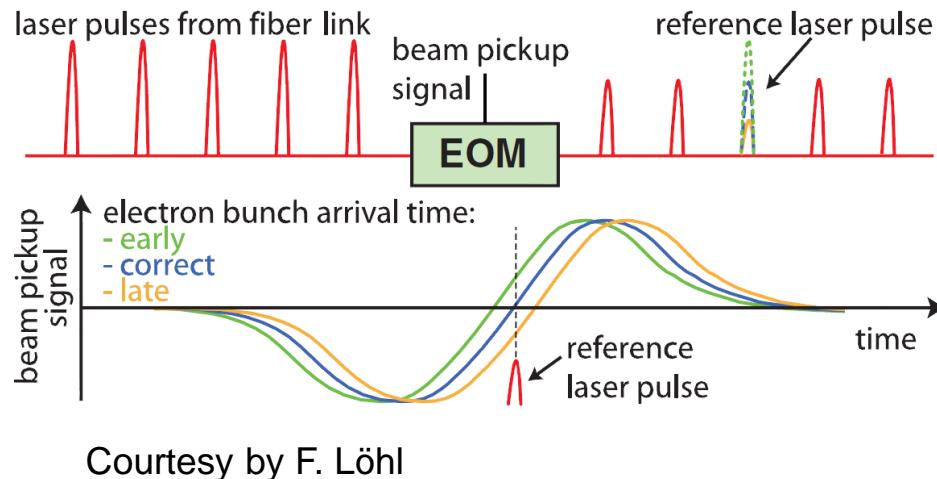
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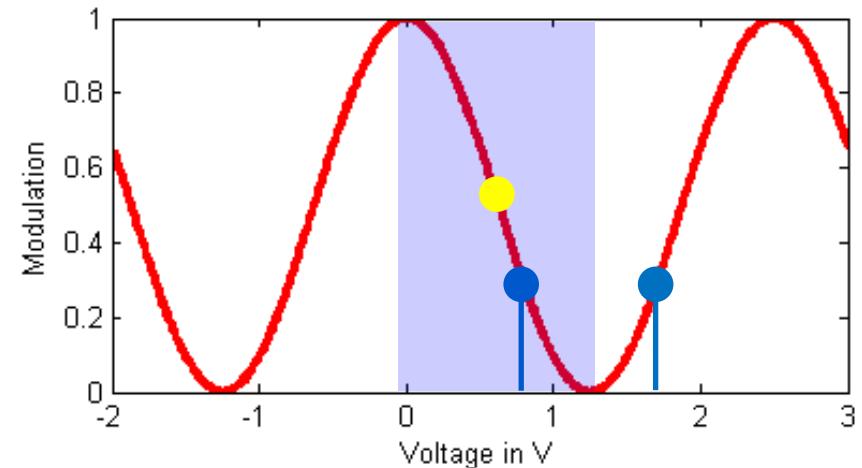
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# Results

## Back to principle of measurement



## Modulation of the laser pulse



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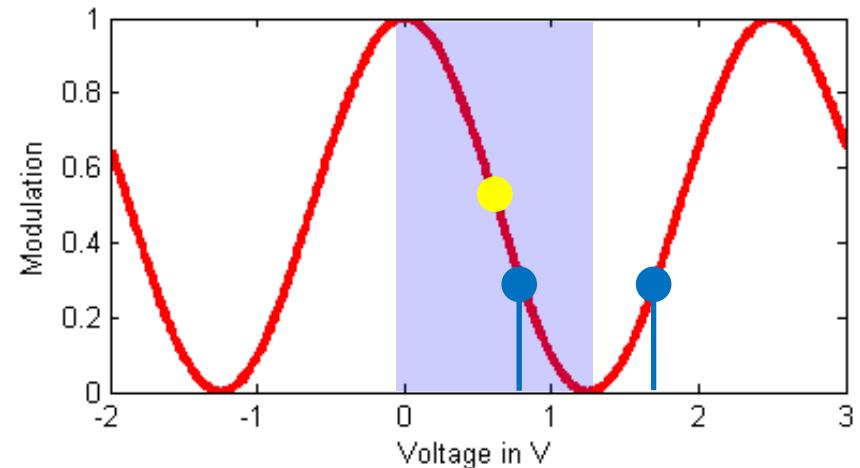
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# Results

## Modulation of the laser pulse



$$M = \frac{I_{out}}{I_{in}} = \frac{1}{2} + \frac{1}{2} \cos \left( \delta_0 + \frac{\pi}{U_\pi} U(t_m) \right)$$

$M$  = Modulation

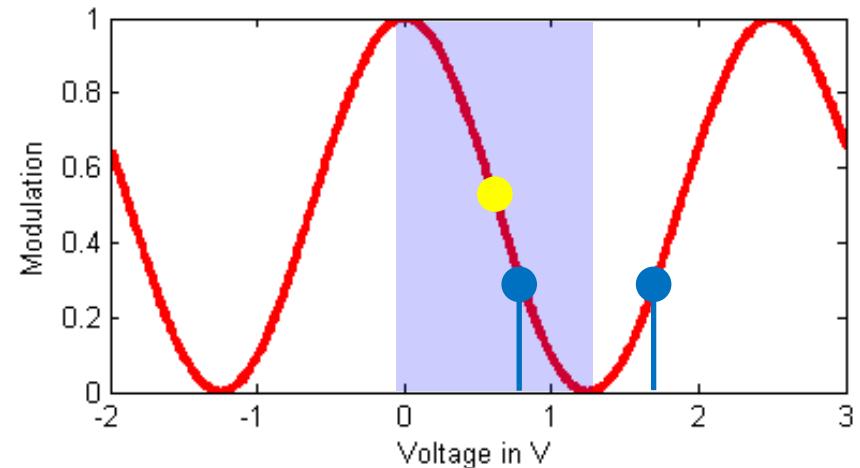
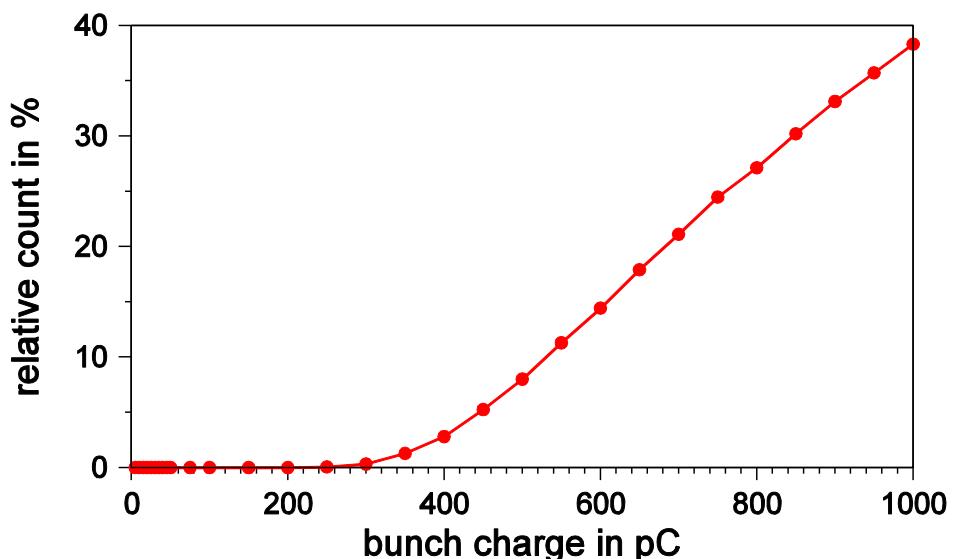
$I$  = Laser amplitude

$\delta_0$  = intrinsic operation point

$U_\pi$  = Voltage to change  $M$  from 0 to 1

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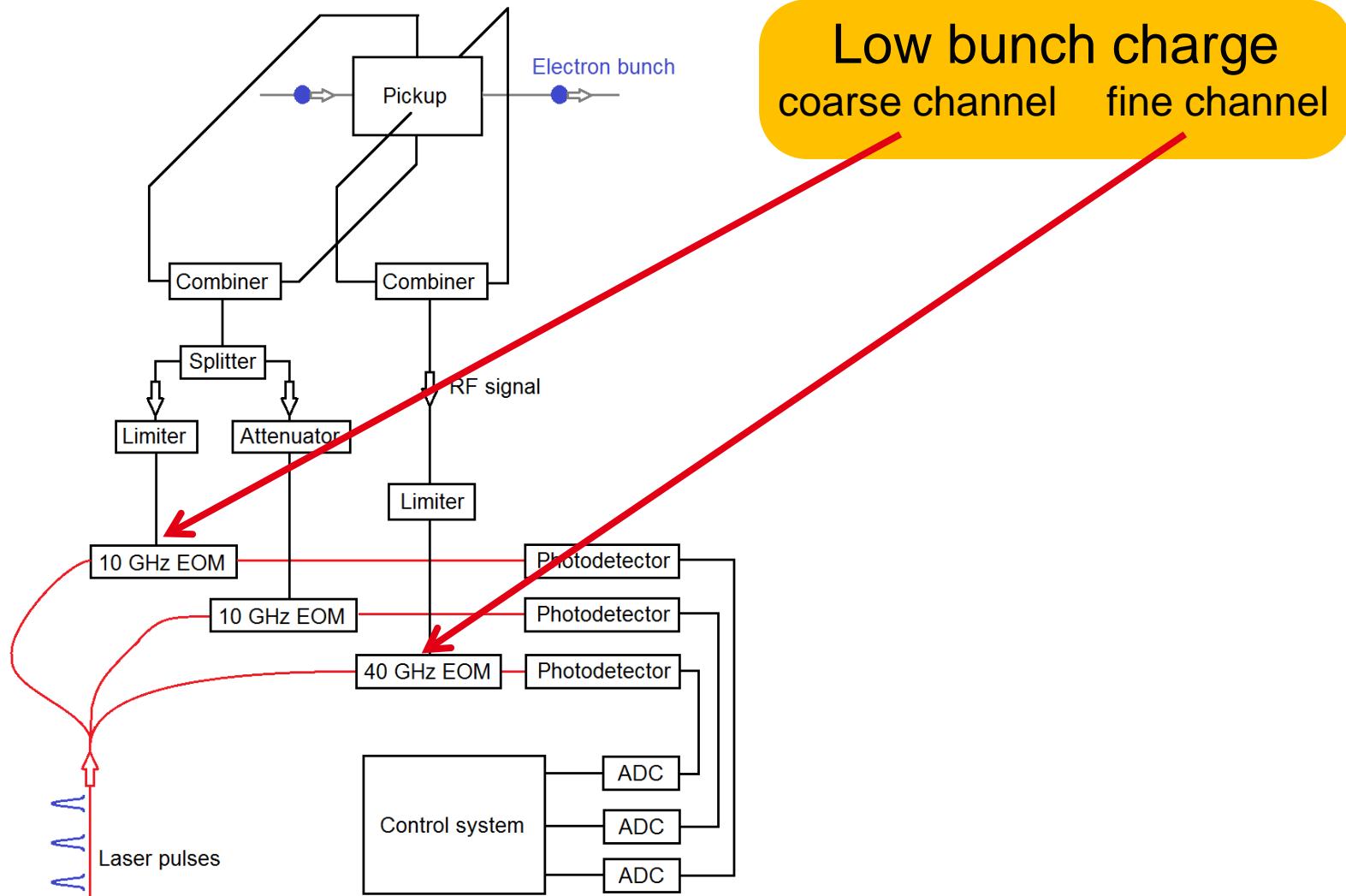
$M$  = Modulation

$I$  = Laser amplitude

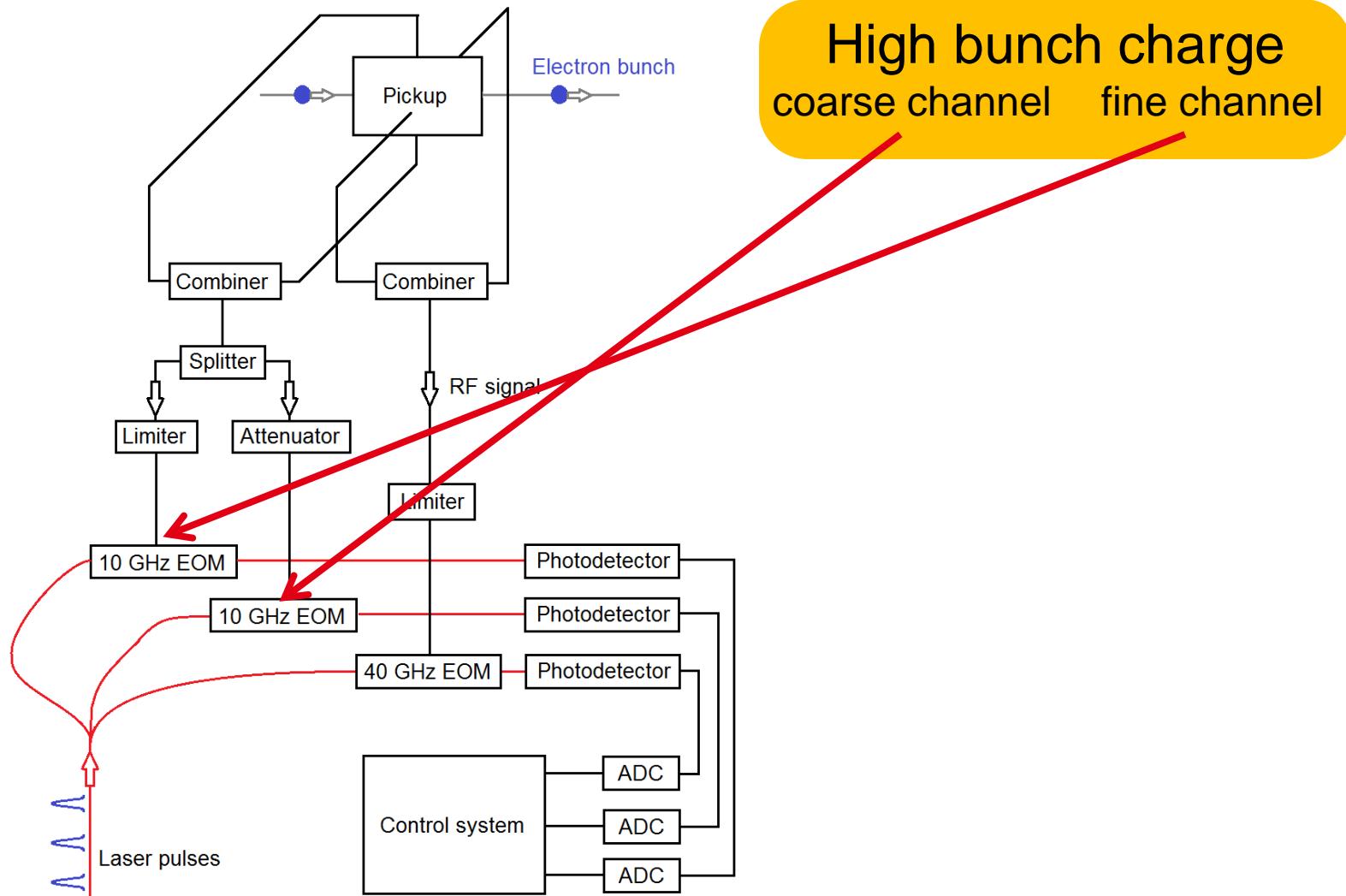
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## Work done

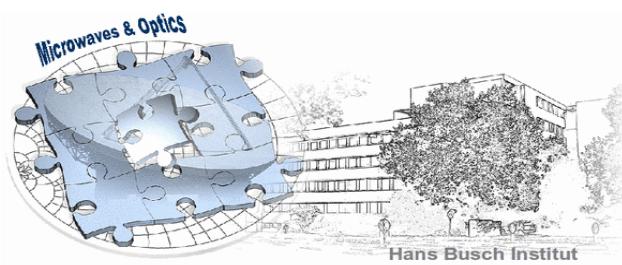
- Design a new pickup
- Manufacturing this new pickup
- Design new front end system
- Installation of the pickup in FLASH

## Future work

- Manufacturing the new front end system
- Measurements with beam
- Integration in the control system
- Upgrade the other 4 BAM-systems



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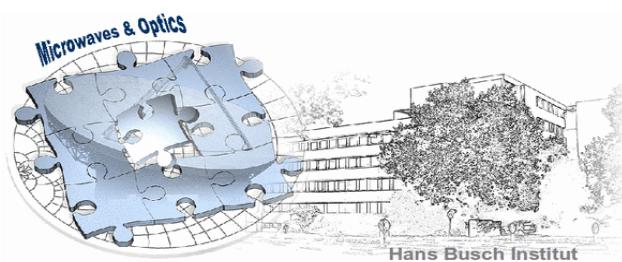
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